Unique Number: 005977

TEST REPORT

Product Name	:	**ICT/ITE POWER SUPPLY**
Model Number	:	**GTM46161-155.0-USB2C, GTM46161-155.0-USBC, GTM46161-165.0-USB1A, GTM46161-165.5-USB2C**

Prepared for	:	GlobTek, Inc.
Address	:	186 VETERANS DRIVE NORTHVALE NJ 07647 United States of America
Prepared by	:	EMTEK (SHENZHEN) CO., LTD.
Address	:	Building 69, Majialong Industry Zone, Nanshan District, Shenzhen, Guangdong, China Tel: (0755) 26954280 Fax: (0755) 26954282

Report Number	:	ENS2512150207E00101R
Date(s) of Tests	:	January 04, 2026 to January 14, 2026
Date of issue	:	January 15, 2026

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APPENDIX A: Photos of EUT (8 Pages)
APPENDIX B: Critical Cmponent List(7 Pages)

TEST REPORT DESCRIPTION

Applicant	:	GlobTek, Inc.
Manufacturer	:	GlobTek, Inc.
Trade Mark	:	G GlobTek, Inc.
EUT	:	ICT/ITE POWER SUPPLY
Model Number	:	GTM46161-155.0-USB2C, GTM46161-155.0-USBC, GTM46161-165.0-USB1A, GTM46161-165.5-USB2C
Unique Number	:	005977
Rating	:	Input: 100-240V~, 50-60Hz, 0.45A GTM46161-155.0-USB2C Output: 5.0V⎓ 3.0A, 15.0W GTM46161-155.0-USBC Output: 5.0V⎓ 3.0A, 15.0W GTM46161-165.0-USB1A Output: 5.0V⎓ 3.2A, 16.0W GTM46161-165.5-USB2C Output: 5.5V⎓ 2.9A, 16.0W

Measurement Procedure Used:

SANS 2332:2017/CISPR 32:2015
SANS 61000-3-2:2009/IEC 61000-3-2:2014, SANS 61000-3-3:2009/IEC 61000-3-3:2013
SANS 2335:2018/CISPR35:2016
(SANS 61000-4-2:2009/IEC 61000-4-2:2008,
SANS 61000-4-3:2008/IEC 61000-4-3:2006+A1:2007+A2:2010,
SANS 61000-4-4:2011/IEC 61000-4-4:2012, SANS 61000-4-5: 2006/IEC 61000-4-5:2014+A1:2017,
SANS 61000-4-6:2017/IEC 61000-4-6:2013, SANS 61000-4-8: 2009/IEC 61000-4-8:2009,
SANS 61000-4-11:2005/IEC 61000-4-11:2004+A1:2017)

The device described above is tested by EMTEK (SHENZHEN) CO., LTD. to determine the maximum emission levels emanating from the device and the severe levels of the device can endure and its performance criterion. The measurement results are contained in this test report and EMTEK (SHENZHEN) CO., LTD. is assumed full of responsibility for the accuracy and completeness of these measurements. Also, this report shows that the EUT (Equipment Under Test) is technically compliant with the SANS 2332/CISPR 32, SANS 61000-3-2/IEC 61000-3-2, SANS 61000-3-3/IEC 61000-3-3 and SANS 2335/CISPR 35 requirements.
This report applies to above tested sample only and shall not be reproduced in part without written approval of EMTEK (SHENZHEN) CO., LTD.

Date of Test	:	January 04, 2026 to January 14, 2026
Prepared by	:	Hu Min/Editor
Reviewer	:	Guo Kaimin/Supervisor
Approved & Authorized Signer	:	Wang Li/Manager

Modified Information

Version	Report No.	Revision Date	Summary
/	ENS2512150207E00101R	/	Original Report

1. DESCRIPTION OF STANDARDS AND RESULTS (EUT)

EMISSION			
Description of Test Item	Standard	Limits	Results
Conducted Emissions From the AC Mains Power Ports	**SANS 2332:2017/CISPR 32:2015**	Class B	Pass
Asymmetric mode conducted emissions at Wired network ports	**SANS 2332:2017/CISPR 32:2015**	Class B	N/A
Radiated emissions at frequencies up to 1 GHz	**SANS 2332:2017/CISPR 32:2015**	Class B	Pass
Radiated emissions at frequencies above 1 GHz	**SANS 2332:2017/CISPR 32:2015**	Class B	N/A
Harmonic Current Emissions	**SANS 61000-3-2:2009/IEC 61000-3-2:2014**	Class A	Pass
Voltage Fluctuation and Flicker	**SANS 61000-3-3:2009/IEC 61000-3-3:2013**	Section 5	Pass

IMMUNITY				
Description of Test Item		Basic Standard	Performance Criteria	Results
Electrostatic Discharge	Enclosure ports	**SANS 61000-4-2:2009/IEC 61000-4-2:2008**	B	Pass
Continuous RF electromagnetic field disturbances	Enclosure ports	**SANS 61000-4-3:2008/IEC 61000-4-3:2006+A1:2007+A2:2010**	A	Pass
Electrical fast transients/burst	AC mains power ports	**SANS 61000-4-4:2011/IEC 61000-4-4:2012**	B	Pass
	Analogue/digital data ports		N/A	N/A
	DC network power ports		N/A	N/A
Surges	AC mains power ports	**SANS 61000-4-5:2006/IEC 61000-4-5:2014+A1:2017**	B	Pass
	Analogue/digital data ports		N/A	N/A
	DC network power ports		N/A	N/A
Continuous induced RF disturbances	AC mains power ports	**SANS 61000-4-6:2017/IEC 61000-4-6:2013**	A	Pass
	Analogue/digital data ports		N/A	N/A
	DC network power ports		N/A	N/A
Power frequency magnetic field	Enclosure ports	**SANS 61000-4-8:2009/IEC 61000-4-8:2009**	A	Pass
Voltage dips and interruptions	AC mains power ports	**SANS 61000-4-11:2005/IEC 61000-4-11:2004+A1:2017**	B,C	Pass
Note: N/A is an abbreviation for Not Applicable.				

2. GENERAL INFORMATION

2.1. Description of Device (EUT)

EUT	:	ICT/ITE POWER SUPPLY
Model Number	:	GTM46161-155.0-USB2C, GTM46161-155.0-USBC, GTM46161-165.0-USB1A, GTM46161-165.5-USB2C (Note: All the models are similar to each other except for model name, PCB Layout, output rating and output port (A, USB C or type C). for trading purpose. We prepare GTM46161-165.5-USB2C and GTM46161-165.0-USB1A for test.)
Applicant	:	GlobTek, Inc.
Address	:	186 VETERANS DRIVE NORTHVALE NJ 07647 United States of America
Manufacturer	:	GlobTek, Inc.
Address	:	186 VETERANS DRIVE NORTHVALE NJ 07647 United States of America
Factory	:	GlobTek (Suzhou) Co., Ltd
Address	:	Building 4, No. 76 JinLing East Road, Suzhou Industrial Park, Suzhou, JiangSu, 215021, China
Date of Received	:	January 04, 2026
Date of Test	:	January 04, 2026 to January 14, 2026

2.2. Independent Operation Modes

A. ON
1. Full Load

2.3. Test Manner

Details of EUT Test Modes:

Test Items	Test Voltage	Function Type	Worst case
Conducted disturbance at mains Terminals	AC 220V/50Hz	Mode A	Mode A
Radiated emissions at frequencies up to 1 GHz	AC 220V/50Hz	Mode A	Mode A
Harmonic Current Emissions	AC 220V/50Hz	Mode A	\
Voltage Fluctuation and Flicker	AC 220V/50Hz	Mode A	\
Electrostatic Discharge	AC 220V/50Hz	Mode A	\
Continuous RF electromagnetic field disturbances	AC 220V/50Hz	Mode A	\
Electrical fast transients/burst	AC 220V/50Hz	Mode A	\
Surges	AC 220V/50Hz	Mode A	\
Continuous induced RF disturbances	AC 220V/50Hz	Mode A	\
Power frequency magnetic field	AC 220V/50Hz	Mode A	\
Voltage dips and interruptions	AC 220V/50Hz	Mode A	\

2.4. Description of Support Device

N/A

2.5. Description of Test Facility

Site Description

EMC Lab. : **Accredited by CNAS**
The Certificate Registration Number is L2291.
The Laboratory has been assessed and proved to be in compliance with CNAS-CL01 (identical to ISO/IEC 17025:2017)

Accredited by FCC
Designation Number: CN1204
Test Firm Registration Number: 882943

Accredited by A2LA
The Certificate Number is 4321.01.

Accredited by Industry Canada
The Conformity Assessment Body Identifier is CN0008

Name of Firm : EMTEK (SHENZHEN) CO., LTD.

Site Location : Building 69, Majialong Industry Zone, Nanshan District, Shenzhen, Guangdong, China

2.6. Measurement Uncertainty

Test Item		Uncertainty
Conducted Emission Uncertainty (Conduction 1#)	:	1.56dB (9k~150kHz Conduction) 1.42dB (150k-30MHz Conduction)
Radiated Emission Uncertainty (3m 1# Chamber)	:	3.92dB (30M~1GHz Polarize: H) 4.54dB (30M~1GHz Polarize: V)
Uncertainty for Flicker test	:	0.514%
Uncertainty for Harmonic test	:	4.04%
Uncertainty for C/S Test	:	0.94dB(Using CDN Test) 2.37dB(Using EM Clamp Test)
Uncertainty for R/S Test	:	1.53dB(80MHz-3000MHz)
Uncertainty for ESD Test	:	6%
Uncertainty for test site temperature and humidity	:	0.6℃ 4%

3. MEASURING DEVICE AND TEST EQUIPMENT

3.1. For Conducted Emissions at the AC Mains Power Ports

Used	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
☑	EMI Test Receiver	Rohde & Schwarz	ESCI	101384	May 09, 2025	1 Year
☑	AMN	Rohde & Schwarz	ENV216	101161	May 09, 2025	1 Year
☑	AMN	Kyoritsu	KNW-407	8-1492-9	May 10, 2025	1 Year

3.2. For Radiated Emission Measurement (3m)

Used	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
☑	EMI Test Receiver	Rohde & Schwarz	ESCI	101414	May 09, 2025	1 Year
☑	Pre-Amplifier	HP	8447F	2944A07999	May 09, 2025	1 Year
☑	Bilog Antenna	Schwarzbeck	VULB9163	141	June 15, 2024	2 Year

3.3. For Harmonic Current / Flicker Measurement

Used	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
☑	45KVA AC Power source	Teseq	NSG 1007-45/45KVA	1305A02873	May 10, 2025	1 Year
☑	Signal conditioning Unit	Teseq	CCN 1000-3	1305A02873	May 10, 2025	1 Year
☑	Impedance network	Teseq	INA2197/37A	1305A02873	May 10, 2025	1 Year
☑	Impedance network	Teseq	INA 2196/75A	1305A02874	May 10, 2025	1 Year
☐	Profline 2100 AC Switching Unit	Teseq	NSG 2200-3	A22714	May 10, 2025	1 Year

3.4. For Electrostatic Discharge Immunity Test

Used	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
☑	ESD Tester	TESEQ	NSG 438	1881	April 27, 2025	1 Year

3.5. For Continuous RF Electromagnetic Field Disturbances Immunity

Used	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
☑	Power Amplifier	MILMEGA	AS0102-55	1018770	May 09, 2025	1 Year
☑	RF Power Meter. Dual Channel	BOONTON	4232A	10539	May 09, 2025	1 Year
☑	Log.-Per. Antenna	SCHWARZBECK	STLP 9129-7/16	3050	N/A	N/A
☑	Signal Generator	Agilent	N5181A	MY50145187	May 09, 2025	1 Year
☑	50ohm Diode Power Sensor	BOONTON	51011EMC	36164	May 09, 2025	1 Year
☑	Field Strength Meter	DARE	RSS1006A	10I00037SNO 22	May 13, 2025	1 Year
☑	Multi-function interface system	DARE	CTR1009B	12I00250SNO 72	N/A	N/A
☑	Automatic switch group	DARE	RSW1004A	N/A	N/A	N/A
☑	Power Amplifier	MILMEGA	AS1860-50	1059346	Nov. 07, 2025	1 Year
☑	Power Amplifier	Vectawave	VBA 1000-600C	133627	Oct. 16, 2025	1 Year

3.6. For Electrical Fast Transient / Burst Immunity Test

Used	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
☑	Burst Tester	Partner	IMU-MGS	109938-1635	Oct. 18, 2025	1 Year
☐	Coupling Clamp	HAEFELY	IP-4A	147147	May 09, 2025	1 Year

3.7. For Surge Immunity Test

Used	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
☑	Controller	HAEFELY	Psurge 8000	174031	May 10, 2025	1 Year
☑	Impulse Module	HAEFELY	PIM 100	174124	Aug. 08, 2025	1 Year
☑	Coupling Decoupling	HAEFELY	PCD 130	172181	May 10, 2025	1 Year
☐	Coupling Module	HAEFELY	PCD122	174354	May 10, 2025	1 Year
☐	Impulse Module	HAEFELY	PIM 120	174435	May 10, 2025	1 Year
☐	Coupling Module	HAEFELY	PCD 126A	174387	Aug. 08, 2025	1 Year
☐	Impulse Module	HAEFELY	PIM 110	174391	May 10, 2025	1 Year
☐	Impulse Module	HAEFELY	PIM 150	178707	May 10, 2025	1 Year
☐	Impulse Module	PMI	PCDN8	190422	Aug. 08, 2025	1 Year

3.8. For Continuous Induced RF Disturbances Immunity Test

Used	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
☑	Continuous Wave Simulator	EMTEST	CWS500C	0900-12	May 11, 2025	1 Year
☐	CDN	EMTEST	CDN-M2	510010010010	May 10, 2025	1 Year
☑	CDN	EMTEST	CDN-M3	0900-11	May 10, 2025	1 Year
☐	EM Injection Clamp	EMTEST	F-2031-23MM	368	May 09, 2025	1 Year
☑	Attenuator	EMTEST	100W 6dB DC-3G	/	May 11, 2025	1 Year
☑	Signal Generator	R&S	SMB100A	103041	May 09, 2025	1 Year
☑	Power meter	AGILENT	E4418B	MY45102886	May 11, 2025	1 Year
☑	Directional coupler	SKET	DC_0110000M-100W	SK2018080301	May 11, 2025	1 Year

3.9. For Power Frequency Magnetic Field Immunity Test

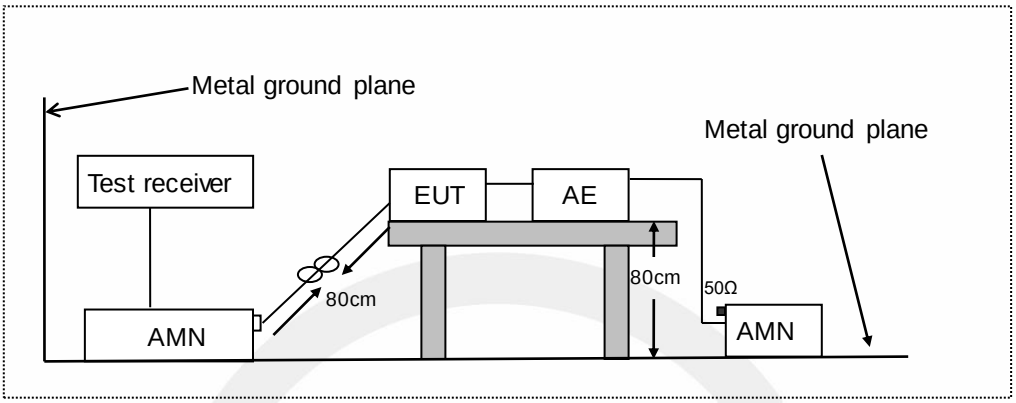
Used	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
☑	Magnetic Field Tester	HAEFELY	MAG100	250040.1	May 10, 2025	1 Year

3.10. For Voltage Dips and Interruptions Immunity Test

Used	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
☑	45KVA AC Power source	Teseq	NSG 1007-45/45KVA	1305A02873	May 10, 2025	1 Year
☐	Signal conditioning Unit	Teseq	CCN 1000-3	1305A02873	May 10, 2025	1 Year
☐	Impedance network	Teseq	INA2197/37A	1305A02873	May 10, 2025	1 Year
☐	Impedance network	Teseq	INA 2196/75A	1305A02874	May 10, 2025	1 Year
☑	Profline 2100 AC Switching Unit	Teseq	NSG 2200-3	A22714	May 10, 2025	1 Year

4. CONDUCTED EMISSIONS FROM THE AC MAINS POWER PORTS

4.1. Block Diagram of Test Setup



AMN: Artificial Mains Network
AE: Associated equipment
EUT: Equipment under test

4.2. Limits

SANS 2332/CISPR 32

Frequency range MHz	Coupling device	Detector type / bandwidth	Class B limits dB(μV)
0.15 to 0.5	AMN	Quasi Peak / 9 kHz	66 to 56
0.5 to 5			56
5 to 30			60
0.15 to 0.5	AMN	Average / 9 kHz	56 to 46
0.5 to 5			46
5 to 30			50

4.3. Test Procedure

The EUT was placed on a desk 0.8 m height from the metal ground plane and 0.4 m from the conducting wall of the shielding room and it was kept at least 0.8 m from any other grounded conducting surface. The size of the table will nominally be 1.5 m x1.0 m.

The rear of the arrangement shall be flush with the back of the supporting tabletop unless that would not be possible or typical of normal use.

All units of equipment forming the system under test (includes the EUT as well as connected peripherals and associated equipment or devices) shall be arranged such that a nominal 0.1 m separation is achieved between the neighboring units.

Connect EUT to the power mains through a artificial mains network (AMN). Where the mains cable supplied by the manufacturer is longer than 1 m, the excess should be folded at the centre into a bundle

no longer than 0.4 m, so that its length is shortened to 1 m.

All the support units are connecting to the other AMN.

The AMN provides 50 ohm coupling impedance for the measuring instrument.

The CISPR states that the AMN with 50 ohm and 50 microhenry should be used.

Both sides of AC line were checked for maximum conducted interference.

The frequency range from 150 kHz to 30 MHz was sweep.

Set the test-receiver system to quasi peak detect function and average detect function, and to measure the conducted emissions values.

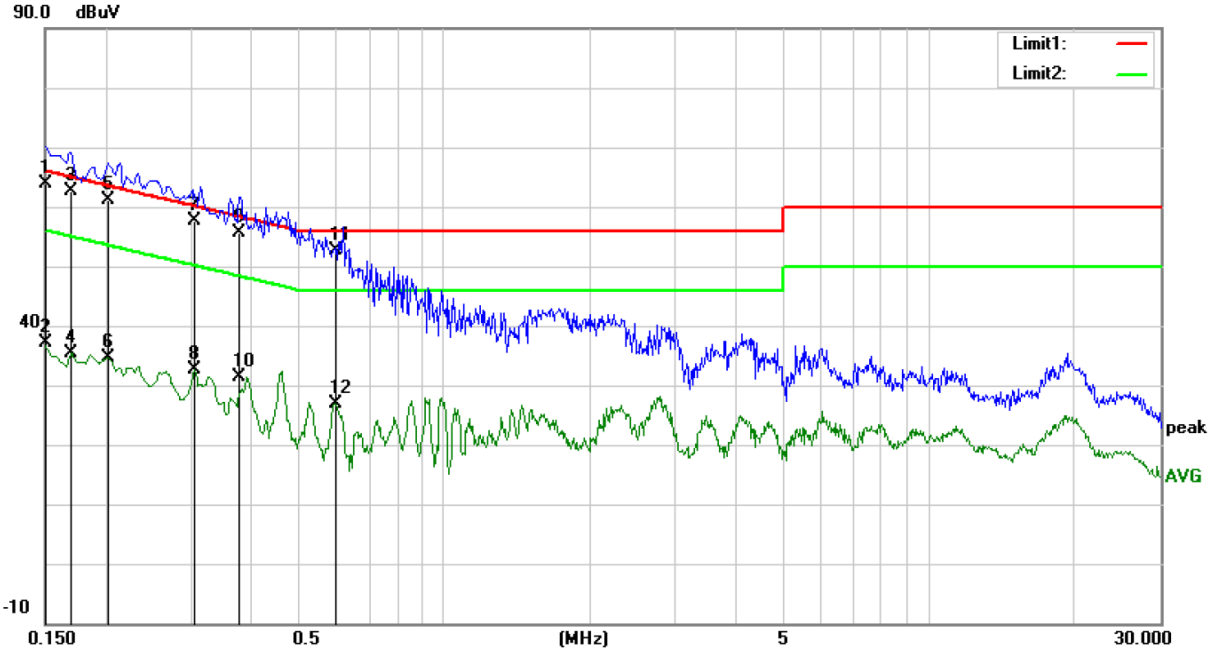
Test results were obtained from the following equation:
Emission Level (dBµV) = AMN Factor (dB) + Cable Loss (dB) + Reading (dBµV)
Margin (dB) = Emission Level (dBµV) - Limit (dBµV)

4.4. Measuring Results

PASS.

All the modes were tested and the data of the worst modes are attached the following pages.

GTM46161-165.5-USB2C



Site Conduction #1 Phase: L1 Temperature: 21.5

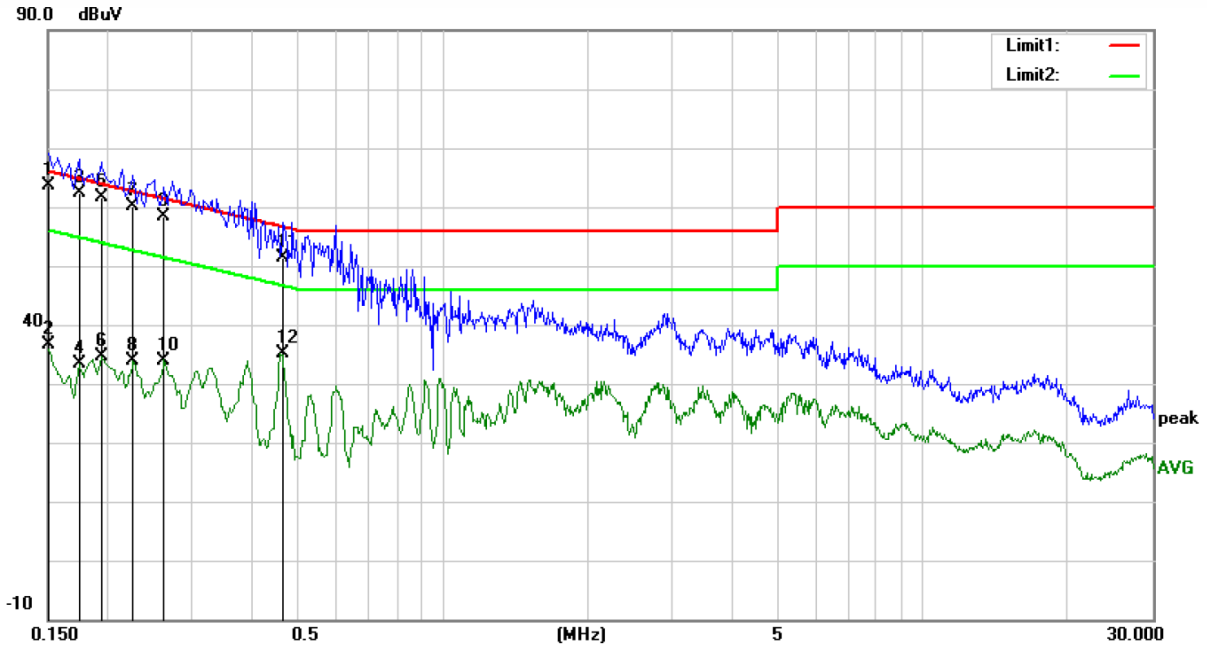
Limit: (CE)CISPR 32 class B_QP Power: AC 220V/50Hz Humidity: 48 %

Mode: Full load

Note:

No.	Mk.	Freq.	Reading Level	Correct Factor	Measure-ment	Limit	Over		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1	*	0.1500	54.09	9.71	63.80	66.00	-2.20	QP	
2		0.1500	27.34	9.71	37.05	56.00	-18.95	AVG	
3		0.1700	52.98	9.72	62.70	64.96	-2.26	QP	
4		0.1700	25.70	9.72	35.42	54.96	-19.54	AVG	
5		0.2020	51.47	9.73	61.20	63.53	-2.33	QP	
6		0.2020	24.94	9.73	34.67	53.53	-18.86	AVG	
7		0.3060	47.87	9.73	57.60	60.08	-2.48	QP	
8		0.3060	22.78	9.73	32.51	50.08	-17.57	AVG	
9		0.3780	45.99	9.71	55.70	58.32	-2.62	QP	
10		0.3780	21.70	9.71	31.41	48.32	-16.91	AVG	
11		0.5980	42.98	9.72	52.70	56.00	-3.30	QP	
12		0.5980	17.15	9.72	26.87	46.00	-19.13	AVG	

*:Maximum data x:Over limit !:over margin Comment: Factor build in receiver. Operator:Huang Junjie



Site Conduction #1 Phase: N Temperature: 21.5

Limit: (CE)CISPR 32 class B_QP Power: AC 220V/50Hz Humidity: 48 %

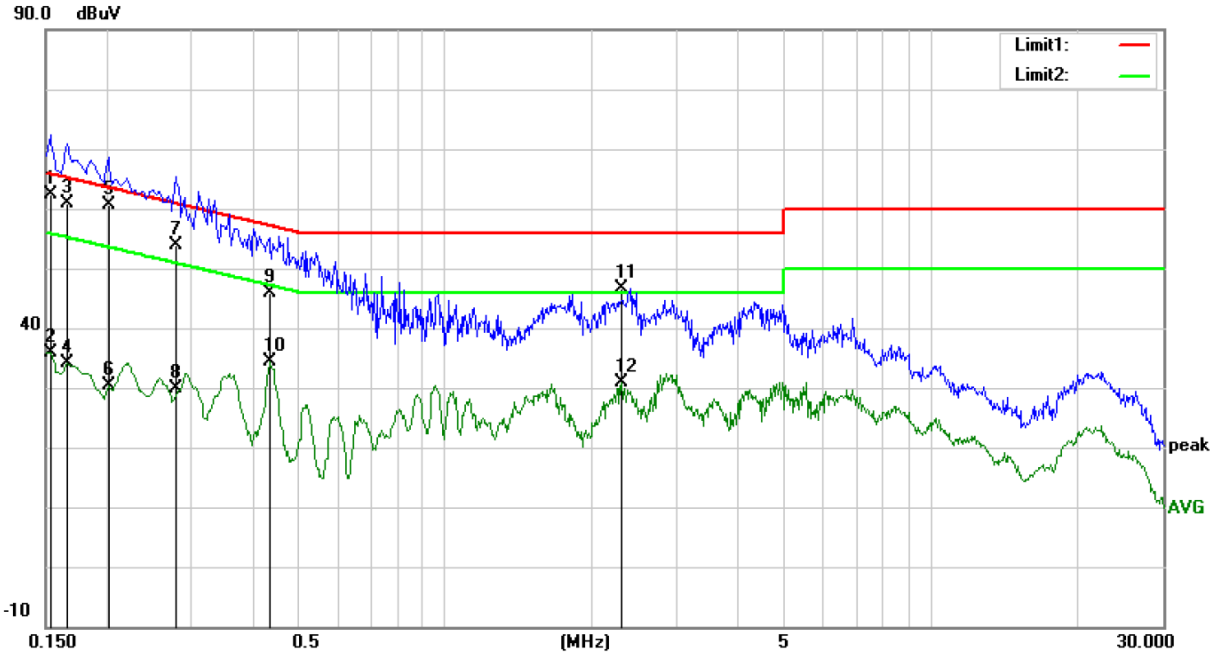
Mode: Full load

Note:

No.	Mk.	Freq.	Reading Level	Correct Factor	Measure-ment	Limit	Over		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1		0.1500	53.99	9.71	63.70	66.00	-2.30	QP	
2		0.1500	26.95	9.71	36.66	56.00	-19.34	AVG	
3		0.1740	52.68	9.72	62.40	64.77	-2.37	QP	
4		0.1740	23.57	9.72	33.29	54.77	-21.48	AVG	
5	*	0.1940	51.97	9.73	61.70	63.86	-2.16	QP	
6		0.1940	24.88	9.73	34.61	53.86	-19.25	AVG	
7		0.2260	50.49	9.71	60.20	62.60	-2.40	QP	
8		0.2260	24.28	9.71	33.99	52.60	-18.61	AVG	
9		0.2620	48.69	9.71	58.40	61.37	-2.97	QP	
10		0.2620	24.29	9.71	34.00	51.37	-17.37	AVG	
11		0.4660	41.58	9.72	51.30	56.58	-5.28	QP	
12		0.4660	25.30	9.72	35.02	46.58	-11.56	AVG	

*:Maximum data x:Over limit !:over margin Comment: Factor build in receiver. Operator:Huang Junjie

GTM46161-165.0-USB1A



Site Conduction #1 Phase: *L1* Temperature: 21.5

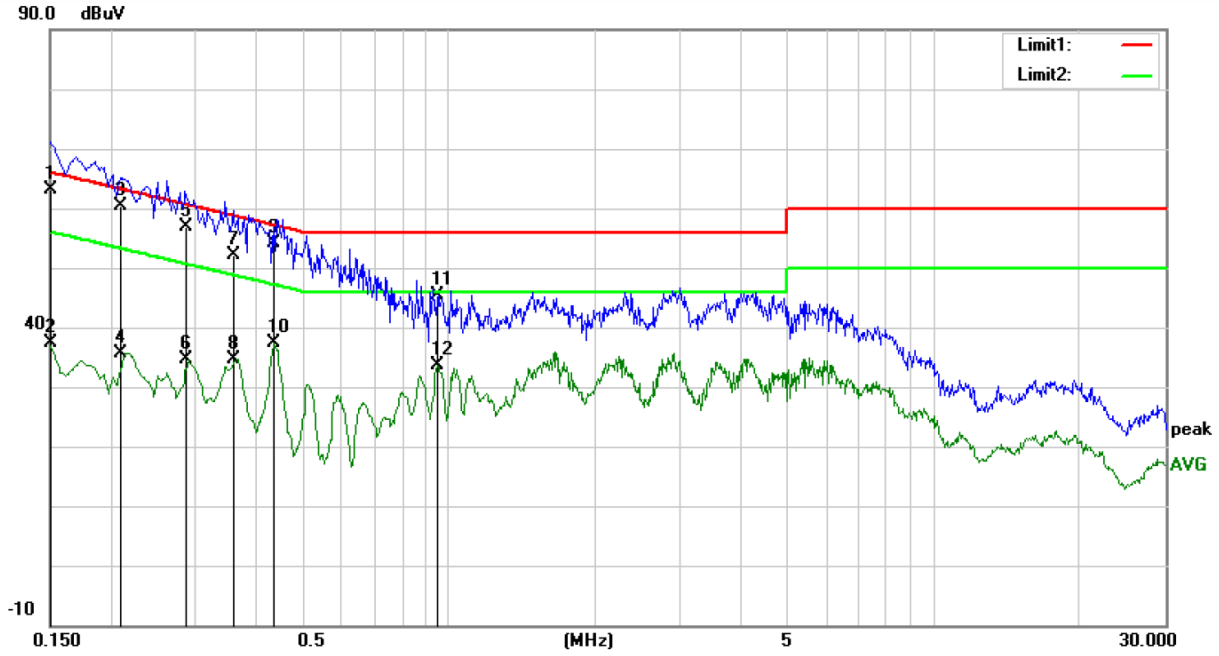
Limit: (CE)CISPR 32 class B_QP Power: AC 220V/50Hz Humidity: 48 %

Mode: Full load

Note:

No.	Mk.	Freq.	Reading Level	Correct Factor	Measure-ment	Limit	Over		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1		0.1540	52.69	9.71	62.40	65.78	-3.38	QP	
2		0.1540	26.19	9.71	35.90	55.78	-19.88	AVG	
3		0.1660	51.18	9.72	60.90	65.16	-4.26	QP	
4		0.1660	24.29	9.72	34.01	55.16	-21.15	AVG	
5	*	0.2020	50.87	9.73	60.60	63.53	-2.93	QP	
6		0.2020	20.66	9.73	30.39	53.53	-23.14	AVG	
7		0.2780	44.28	9.72	54.00	60.88	-6.88	QP	
8		0.2780	20.13	9.72	29.85	50.88	-21.03	AVG	
9		0.4340	36.09	9.71	45.80	57.18	-11.38	QP	
10		0.4340	24.59	9.71	34.30	47.18	-12.88	AVG	
11		2.2980	36.91	9.76	46.67	56.00	-9.33	QP	
12		2.2980	21.00	9.76	30.76	46.00	-15.24	AVG	

*:Maximum data x:Over limit !:over margin Comment: Factor build in receiver. Operator: Huang Junjie



Site Conduction #1 Phase: N Temperature: 21.5

Limit: (CE)CISPR 32 class B_QP Power: AC 220V/50Hz Humidity: 48 %

Mode: Full load

Note:

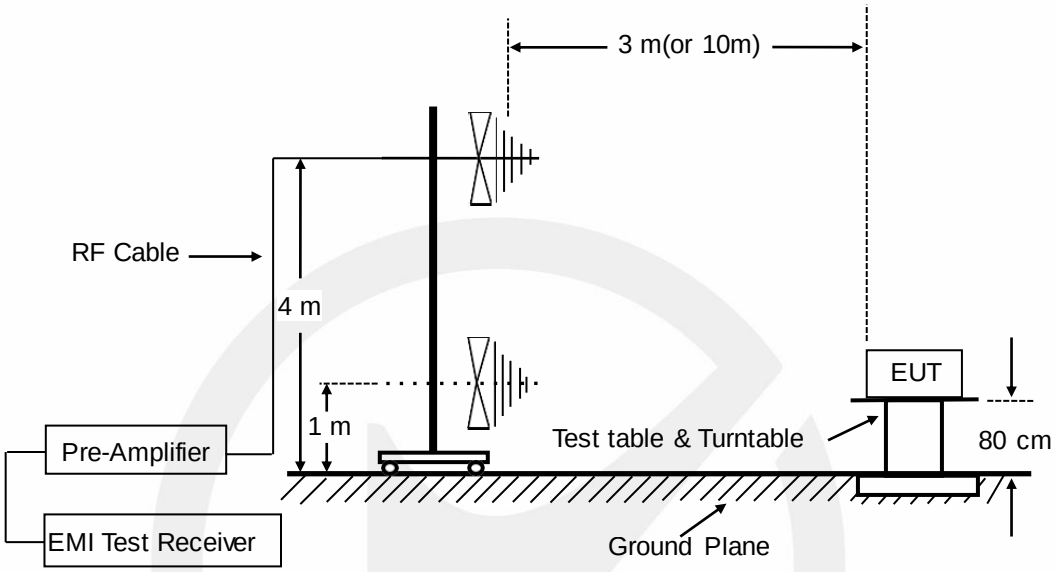
No.	Mk.	Freq.	Reading Level	Correct Factor	Measure-ment	Limit	Over		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1	*	0.1500	53.49	9.71	63.20	66.00	-2.80	QP	
2		0.1500	27.75	9.71	37.46	56.00	-18.54	AVG	
3		0.2100	50.58	9.72	60.30	63.21	-2.91	QP	
4		0.2100	25.86	9.72	35.58	53.21	-17.63	AVG	
5		0.2863	47.08	9.72	56.80	60.63	-3.83	QP	
6		0.2863	24.83	9.72	34.55	50.63	-16.08	AVG	
7		0.3580	42.37	9.73	52.10	58.77	-6.67	QP	
8		0.3580	24.93	9.73	34.66	48.77	-14.11	AVG	
9		0.4340	44.39	9.71	54.10	57.18	-3.08	QP	
10		0.4340	27.63	9.71	37.34	47.18	-9.84	AVG	
11		0.9460	35.59	9.71	45.30	56.00	-10.70	QP	
12		0.9460	23.94	9.71	33.65	46.00	-12.35	AVG	

*:Maximum data x:Over limit !:over margin Comment: Factor build in receiver. Operator:Huang Junjie

5. RADIATED EMISSION MEASUREMENT (UP TO 1GHz)

5.1. Block Diagram of Test Setup

UP TO 1GHz:



5.2. Measuring Standard

SANS 2332/CISPR 32

Frequency range MHz	Measurement			Class B limits dB(μV/m)
	Facility	Distance (m)	Detector type / bandwidth	
30 to 230	OATS/SAC	10	Quasi Peak / 120 kHz	30
230 to 1 000				37
30 to 230	OATS/SAC	3		40
230 to 1 000				47

5.3. Test Procedure

The EUT was placed on a non-conductive table whose total height equaled 80cm. All units of equipment forming the system under test (includes the EUT as well as connected peripherals and associated equipment or devices) shall be arranged such that a nominal 0.1 m separation is achieved between the neighboring units. Where the mains cable supplied by the manufacturer is longer than 1 m, the excess should be folded at the centre into a bundle no longer than 0.4 m, so that its length is shortened to 1 m.

The EUT was set 3 meters (or 10 meters) away from the receiving antenna that was mounted on a non-conductive mast. The antenna can move up and down between 1 to 4 meters to find out the maximum emission level.

The turntable can rotate 360 degree to determine the position of the maximum emission level.

The initial testing identified the frequency that has the highest disturbance relative to the limit while operating the EUT in typical modes of operation and cable positions in a test setup representative of typical system configuration.

The identification of the frequency of highest emission with respect to the limit was found by investigating emissions at a number of significant frequencies. The probable frequency of maximum emission had been found and that the associated cable and EUT configuration and mode of operation had been identified.

The bandwidth of the Receiver is set at 120 kHz.

Test results were obtained from the following equation:
Emission level (dBμV/m) = Antenna Factor -Amp Factor +Cable Loss + Reading
Margin (dB) = Emission Level (dBμV/m) - Limit (dBμV/m)

5.4. Measuring Results

PASS.

All the modes were tested and the data of the worst modes are attached the following pages.

GTM46161-165.5-USB2C



Site 3m Chamber #1 Polarization: *Horizontal* Temperature: 22.3 C

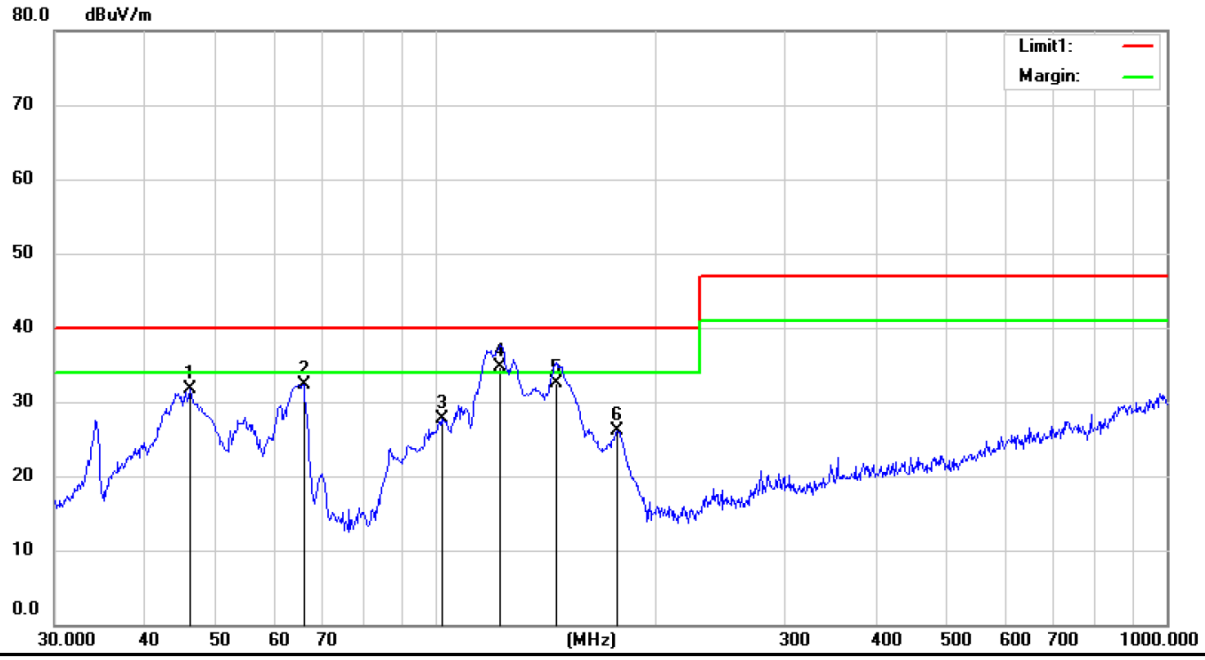
Limit: (RE)CISPR32 ClassB Power: AC 220V/50Hz Humidity: 46 %

Mode: Full load

Note:

No.	Mk.	Freq.	Reading Level	Correct Factor	Measure-ment	Limit	Over		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector	cm	degree	Comment
1		46.5846	34.21	-10.82	23.39	40.00	-16.61	QP			
2		63.8427	35.71	-13.21	22.50	40.00	-17.50	QP			
3		116.6934	33.09	-13.49	19.60	40.00	-20.40	QP			
4	*	145.3506	43.10	-14.97	28.13	40.00	-11.87	QP			
5		174.0422	34.29	-14.31	19.98	40.00	-20.02	QP			
6		293.3413	33.48	-9.16	24.32	47.00	-22.68	QP			

*:Maximum data x:Over limit !:over margin Operator: Yin Jiezhe



Site 3m Chamber #1 Polarization: *Vertical* Temperature: 22.3 C

Limit: (RE)CISPR32 ClassB Power: AC 220V/50Hz Humidity: 46 %

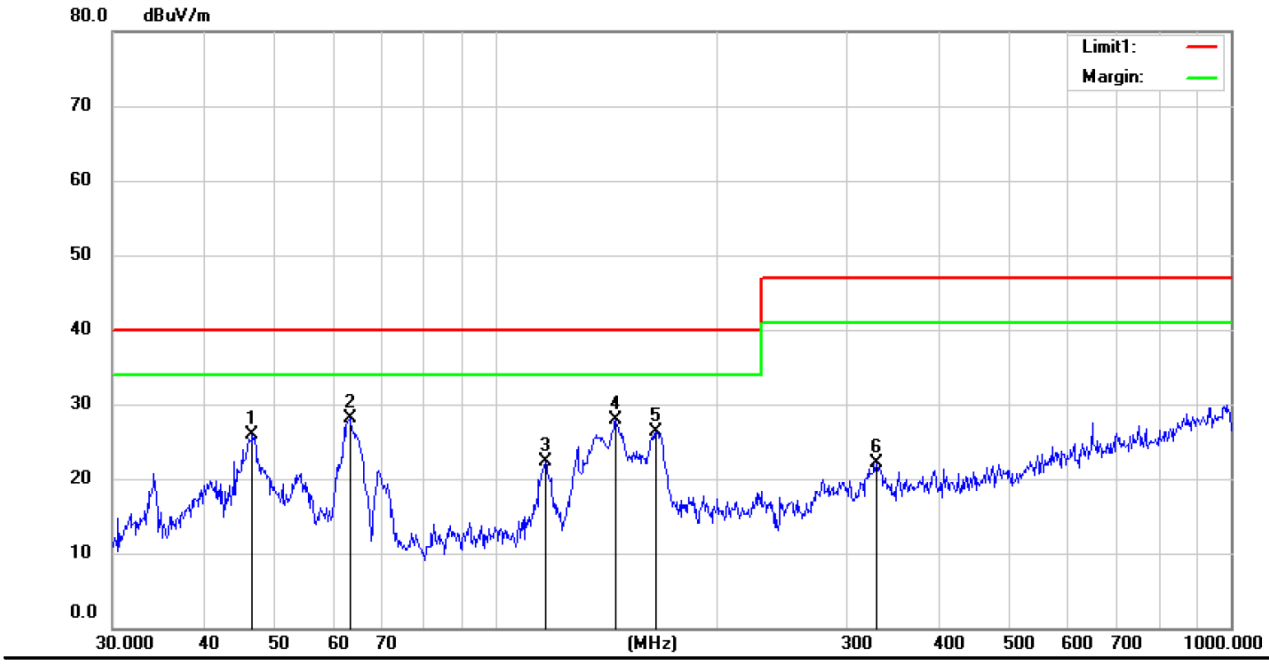
Mode: Full load

Note:

No.	Mk.	Freq.	Reading Level	Correct Factor	Measure-ment	Limit	Over		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector	cm	degree	Comment
1		46.1375	42.62	-10.97	31.65	40.00	-8.35	QP			
2		65.7165	46.05	-13.71	32.34	40.00	-7.66	QP			
3		101.8673	40.37	-12.58	27.79	40.00	-12.21	QP			
4	*	122.8340	49.24	-14.44	34.80	40.00	-5.20	QP			
5		146.0530	47.63	-15.03	32.60	40.00	-7.40	QP			
6		177.2760	40.35	-14.33	26.02	40.00	-13.98	QP			

*:Maximum data x:Over limit !:over margin Operator: Yin Jiezhe

GTM46161-165.0-USB1A



Site 3m Chamber #1 Polarization: *Horizontal* Temperature: 22.3 C

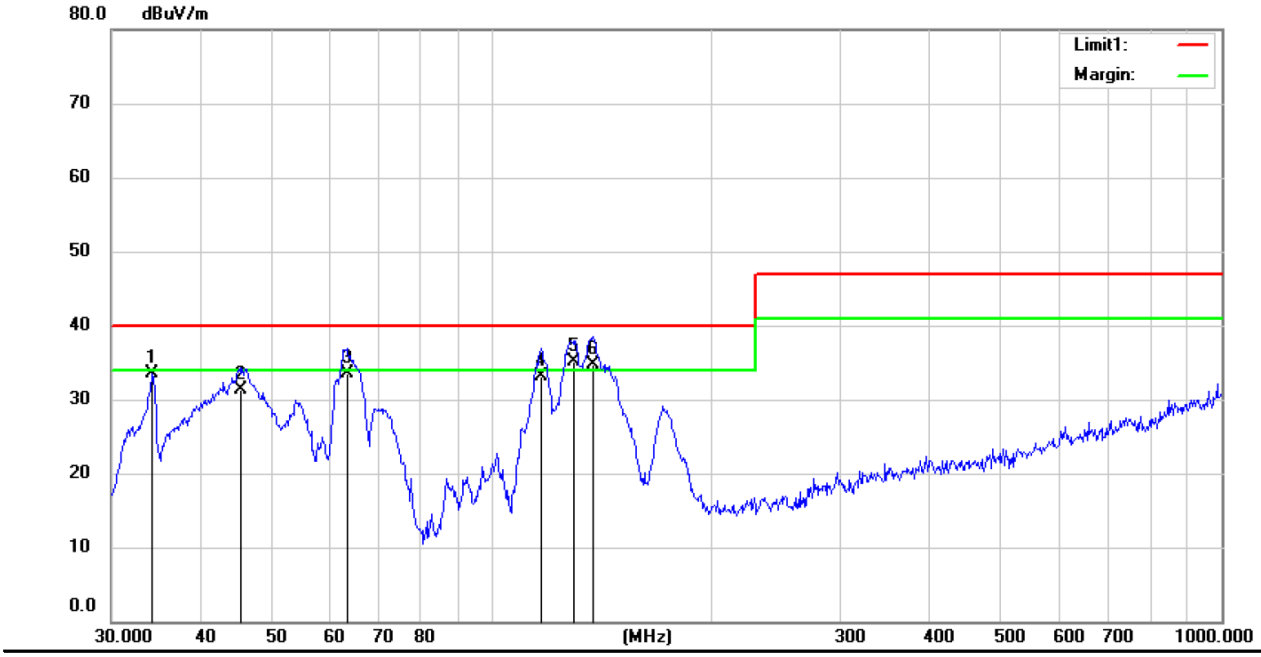
Limit: (RE)CISPR32 ClassB Power: AC 220V/50Hz Humidity: 46 %

Mode: Full load

Note:

No.	Mk.	Freq.	Reading Level	Correct Factor	Measure-ment	Limit	Over		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector	cm	degree	Comment
1		46.5234	36.78	-10.84	25.94	40.00	-14.06	QP			
2	*	63.1192	41.07	-13.02	28.05	40.00	-11.95	QP			
3		116.6422	35.79	-13.48	22.31	40.00	-17.69	QP			
4		145.7972	42.93	-15.00	27.93	40.00	-12.07	QP			
5		164.9797	40.48	-14.21	26.27	40.00	-13.73	QP			
6		329.9055	30.28	-8.12	22.16	47.00	-24.84	QP			

*:Maximum data x:Over limit !:over margin Operator: Yin Jiezhe



Site 3m Chamber #1
Polarization: *Vertical*
Temperature: 22.3 C

Limit: (RE)CISPR32 ClassB
Power: AC 220V/50Hz
Humidity: 46 %

Mode: Full load

Note:

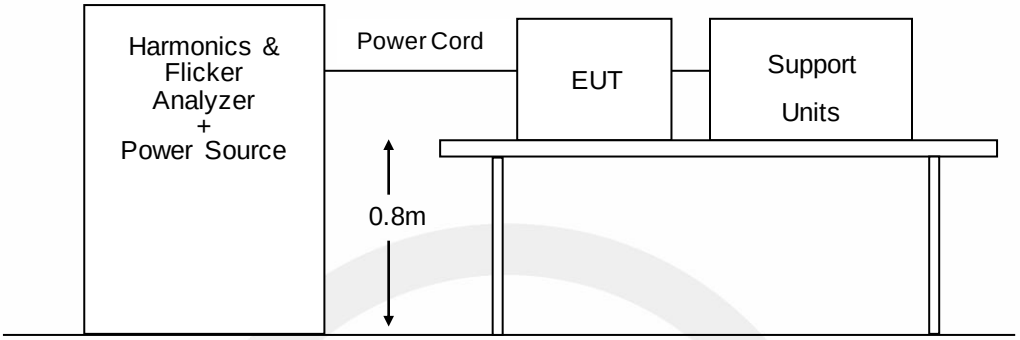
No.	Mk.	Freq.	Reading Level	Correct Factor	Measure-ment	Limit	Over		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector	cm	degree	Comment
1		34.2160	47.59	-14.03	33.56	40.00	-6.44	QP			
2		45.3754	42.63	-11.33	31.30	40.00	-8.70	QP			
3		63.1192	46.62	-13.02	33.60	40.00	-6.40	QP			
4		116.8982	46.74	-13.54	33.20	40.00	-6.80	QP			
5	*	129.0711	50.02	-14.92	35.10	40.00	-4.90	QP			
6	!	137.8425	50.24	-15.44	34.80	40.00	-5.20	QP			

*:Maximum data x:Over limit !:over margin

Operator: Yin Jiezhe

6. HARMONIC CURRENT EMISSION MEASUREMENT

6.1. Block Diagram of Test Setup



6.2. Standard Limits

SANS 61000-3-2/IEC 61000-3-2, CLASS A
Harmonic current emissions evaluate the potential for the EUT to cause distortion on the AC power lines. It is applicable to electrical and electronic equipment having an input current≤16 A per phase, and intended to be connected to public low-voltage distribution systems

Table 1 - Limits for Class A equipment

Harmonic order n	Maximum permissible harmonic current (A)
Odd harmonics	
3	2.30
5	1.14
7	0.77
9	0.40
11	0.33
13	0.21
$15 \le n \le 39$	$0.15 \frac{0.15}{n}$
Even harmonics	
2	1.08
4	0.43
6	0.30
$8 \le n \le 40$	$0.23 \frac{8}{n}$

6.3. Test Procedure

The measurement of harmonic currents shall be performed as follows: i. For each harmonic order, measure the 1.5 s smoothed r.m.s. harmonic current in each DFT time window as defined in EN / IEC 61000-4-7:2009. ii. Calculate the arithmetic average of the measured values from the DFT time windows, over the entire observation period Short cyclic (T cycle≤2.5 min). Because of synchronisation to meet the requirements for repeatability in 5%.

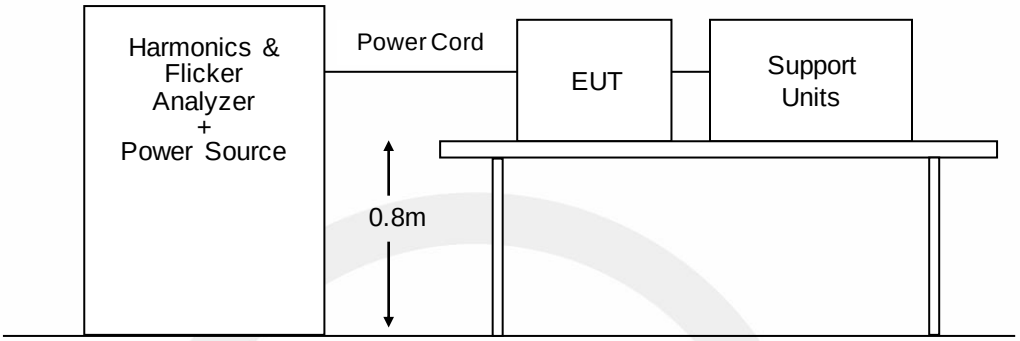
6.4. Test Results

N/A.

As specified on section 7 and above figure of EN 61000-3-2, the limits are not specified for equipment with a rated power of 75W or less. The EUT meets the above condition, so it conforms to EN 61000-3-2.

7. VOLTAGE FLUCTUATION AND FLICKER MEASUREMENT

7.1. Block Diagram of Test Setup



7.2. Standard Limits

SANS 61000-3-3/IEC 61000-3-3 Limits
The objective of voltage changes, voltage fluctuations and flicker in public low voltage supply systems during equipment with rated current≤16 A per phase, ensures that home appliances and certain other electrical equipment do not adversely affect lighting equipment when connected to the same power system.
Voltage Fluctuation and Flicker Limits:
— the value of Pst shall not be greater than 1.0;
— the value of Plt shall not be greater than 0.65;
— the value of d(t) during a voltage change shall not exceed 3.3 % for more than 500 ms;
— the relative steady-state voltage change, dc, shall not exceed 3.3 %;
— the maximum relative voltage change, dmax, shall not exceed 4.0 %;

7.3. Test Procedure

The total impedance of the test circuit, excluding the appliance under test, but including the internal impedance of the supply source, shall be equal to the reference impedance. The stability and tolerance of the reference impedance shall be adequate to ensure that the overall accuracy of 8% is achieved during the whole assessment procedure.

7.4. Test Results

PASS.

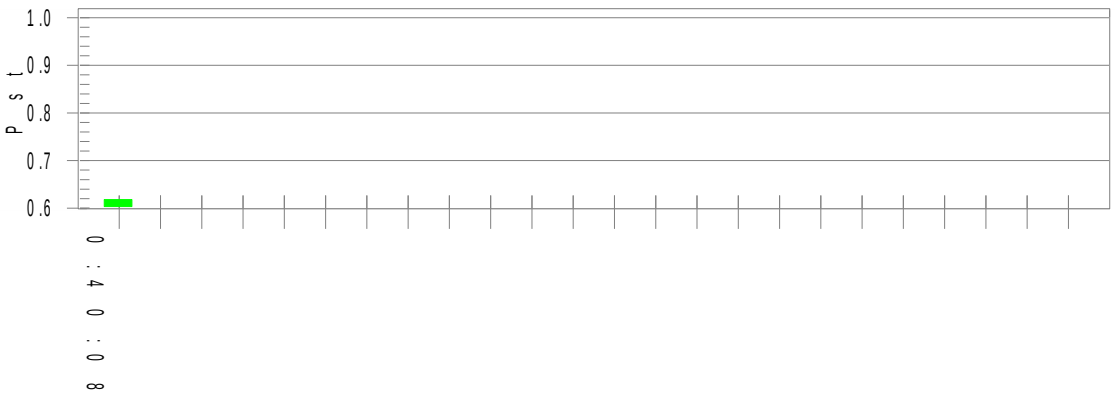
Please see the attached page.

Flicker Test Summary per EN/IEC61000-3-3 (Run time)

EUT: ICT/ITE POWER SUPPLY **Tested by: Zhuo Guixin**
Test category: All parameters (European limits) **Test Margin: 100**
Test date: 2026/1/5 **Start time: 0:29:47** **End time: 0:40:14**
Test duration (min): 10 **Data file name: CTSL_F-000109.cts_data**
Comment: Full Load
Customer: GlobTek, Inc.

Test Result: Pass **Status: Test Completed**

Pst_i and limit line **European Limits**



Parameter values recorded during the test:

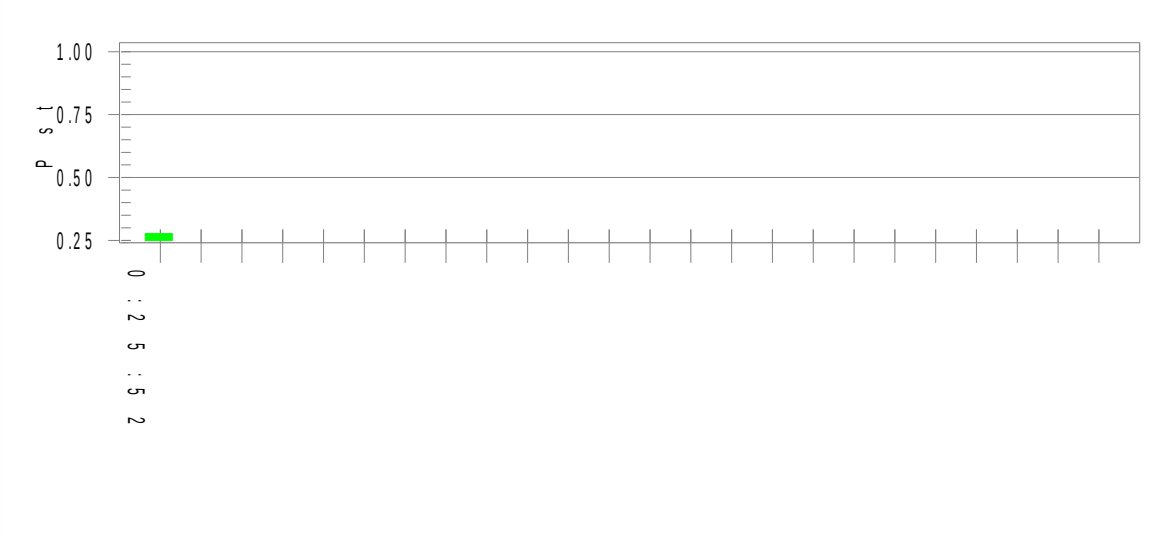
Vrms at the end of test (Volt):	**220.61**			
T-max (mS):	**0.0**	**Test limit (mS):**	**500.0**	**Pass**
Highest dc (%):	**0.00**	**Test limit (%):**	**3.30**	**Pass**
Highest dmax (%):	**-0.04**	**Test limit (%):**	**4.00**	**Pass**
Highest Pst (10 min. period):	**0.618**	**Test limit:**	**1.000**	**Pass**

Flicker Test Summary per EN/IEC61000-3-3 (Run time)

EUT: ICT/ITE POWER SUPPLY **Tested by: Zhuo Guixin**
Test category: All parameters (European limits) **Test Margin: 100**
Test date: 2026/1/5 **Start time: 0:15:31** **End time: 0:25:58**
Test duration (min): 10 **Data file name: CTSL_F-000108.cts_data**
Comment: Full load
Customer: GlobTek, Inc.

Test Result: Pass **Status: Test Completed**

Pst_i and limit line **European Limits**



Parameter values recorded during the test:

Vrms at the end of test (Volt):	**220.58**			
T-max (mS):	**0.0**	**Test limit (mS):**	**500.0**	**Pass**
Highest dc (%):	**0.00**	**Test limit (%):**	**3.30**	**Pass**
Highest dmax (%):	**-0.06**	**Test limit (%):**	**4.00**	**Pass**
Highest Pst (10 min. period):	**0.277**	**Test limit:**	**1.000**	**Pass**

8. IMMUNITY PERFORMANCE CRITERIA DESCRIPTION

Performance Level

The test results shall be classified in terms of the loss of function or degradation of performance of the equipment under test, relative to a performance level by its manufacturer or the requestor of the test, or the agreed between the manufacturer and the purchaser of the product.

Definition related to the performance level:
1. Based on the used product standard
2. Based on the declaration of the manufacturer, requestor or purchaser

SANS 2335/CISPR 35:

Performance criterion A
The equipment shall continue to operate as intended without operator intervention. No degradation of performance, loss of function or change of operating state is allowed below a performance level specified by the manufacturer when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

Performance criterion B
During the application of the disturbance, degradation of performance is allowed. However, no unintended change of actual operating state or stored data is allowed to persist after the test.
After the test, the equipment shall continue to operate as intended without operator intervention; no degradation of performance or loss of function is allowed, below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.
If the minimum performance level (or the permissible performance loss), or recovery time, is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

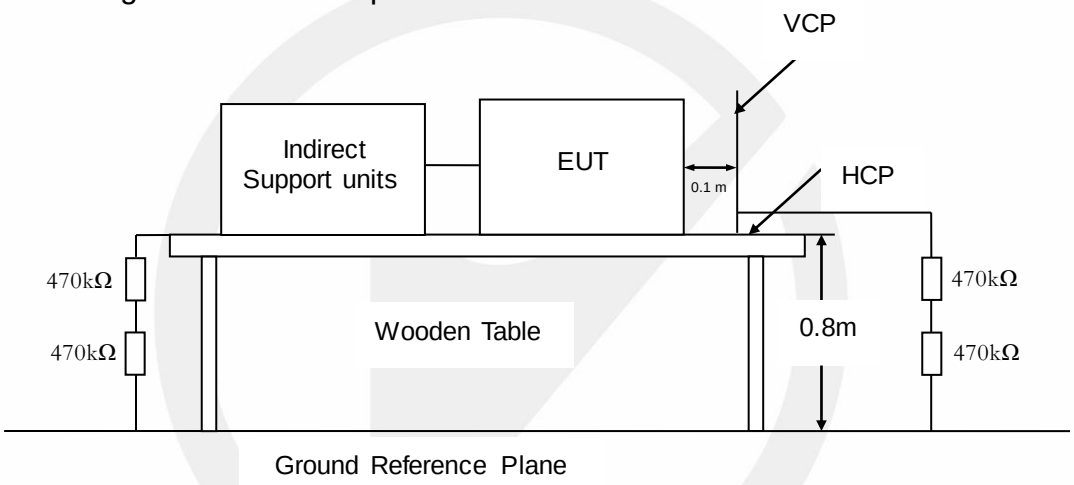
Performance criterion C
Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. A reboot or re-start operation is allowed. Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

9. ELECTROSTATIC DISCHARGE

9.1. Test Specification

Test Standard	:	SANS 2335/CISPR 35
Basic Standard	:	IEC 61000-4-2
Performance criterion	:	B
Test level	:	±8.0kV (Air discharge) ±4.0kV (Contact discharge)

9.2. Block Diagram of Test Setup



9.3. Test Procedure

a. In the case of air discharge testing, the climatic conditions shall be within the following ranges:
- ambient temperature: 15°C to 35°C;
- relative humidity : 30% to 60%;
- atmospheric pressure : 86 kPa (860 mbar) to 106 kPa (1060 mbar)

b. Test programs and software shall be chosen so as to exercise all normal modes of operation of the EUT. The use of special exercising software is encouraged, but permitted only where it can be shown that the EUT is being comprehensively exercised.

c. In the case of contact discharges, the tip of the discharge electrode shall touch the EUT before the discharge switch is operated.

d. In the case of painted surface covering a conducting substrate, the following procedure shall be adopted : - If the coating is not declared to be an insulating coating by the equipment manufacturer, then the pointed tip of the generator shall penetrate the coating so as to make contact with the conducting substrate. - Coating declared as insulating by the manufacturer shall only be submitted to the air discharge. - The contact discharge test shall not be applied to such surfaces.

e. In the case of air discharges, the round discharge tip of the discharge electrode shall be approached as fast as possible (without causing mechanical damage) to touch the EUT. After each discharge, the ESD generator (discharge electrode) shall be removed from the EUT. The generator is then retriggered for a new single discharge. This procedure shall be repeated until the discharges are completed. In the case of an air discharge test, the discharge switch, which is used for contact discharge, shall be closed.

f. The test voltage shall be increased from the minimum to the selected test severity level, in order to determine any threshold of failure. The final test level should not exceed the product specification value in order to avoid damage to the equipment.
g. The test shall be performed with both air discharge and contact discharge. The test shall be performed with single discharges. On each pre-selected point at least 10 single discharges (in the most sensitive polarity) shall be applied. For the time interval between successive single discharges an initial value of 1 s is recommended. Longer intervals may be necessary to determine whether a system failure has occurred.
h. Ensure that the applied charge on the EUT has been dis-charged before next ESD pulse.

9.4. Test Results

PASS

Temperature	:	18.7°C
Humidity	:	43%
Atmospheric Pressure	:	101kpa
Test Engineer	:	Zhuo Guixin
Test Date	:	2025-01-04

Air Discharge:

Test Voltage	Location	Actual criterion	Required performance criterion	Result (Pass/Fail)
±2; 4; 8 kV	SLOT	A	B	Pass

Contact Discharge

Test Voltage	Location	Actual criterion	Required performance criterion	Result (Pass/Fail)
±2; 4kV	/	/	B	/

Indirect Discharge

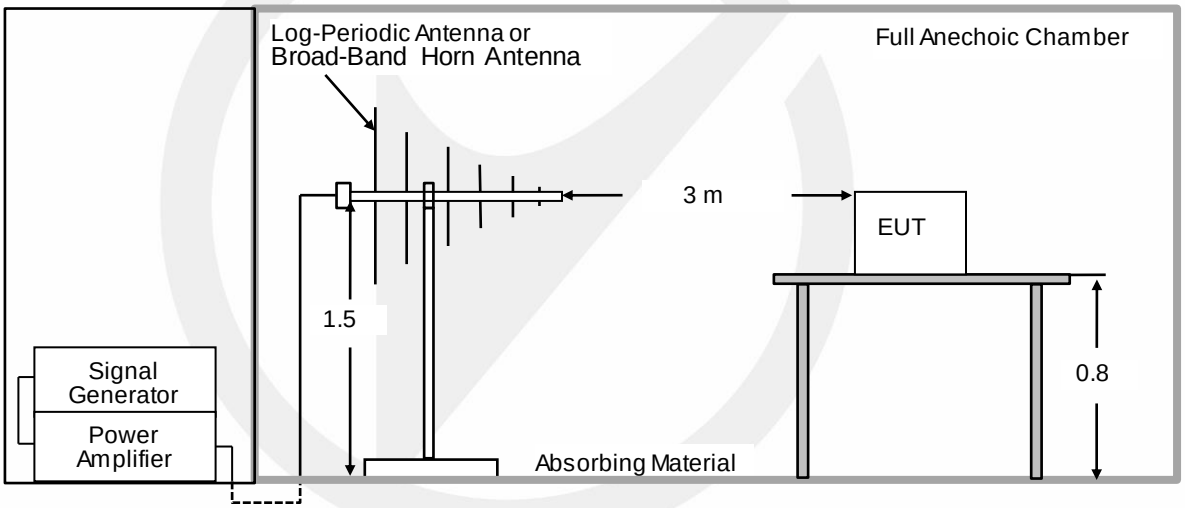
Test Voltage	Location	Actual criterion	Required performance criterion	Result (Pass/Fail)
±2; 4 kV	HCP	A	B	Pass
±2; 4kV	VCP	A	B	Pass

10.CONTINUOUS RF ELECTROMAGNETIC FIELD DISTURBANCES

10.1.Test Specification

Test standard	:	SANS 2335/CISPR 35	
Basic standard	:	IEC 61000-4-3	
Performance criterion	:	A	
Frequency range & Test level	:	☒80M-1000MHz	3V/m
		☒Spot frequency	3V/m
		☐Additional spot frequency	3V/m
Modulation	:	AM, 80%, 1kHz sine-wave	

10.2.Block Diagram of Test Setup



10.3.Test procedure

The procedure defined in this part requires the generation of electromagnetic fields within which the test sample is placed and its operation observed. To generate fields that are useful for simulation of actual (field) conditions may require significant antenna drive power and the resultant high field strength levels. To comply with local regulations and to prevent biological hazards to the testing personnel, it is recommended that these tests be carried out in a shielded enclosure or semi-anechoic chamber.

a. The antenna which is enabling the complete frequency range of 80-1000 MHz is placed 3m (or 1m) away from the equipment. The required field strength is determined by placing the field strength meter(s) on top of or directly alongside the equipment under test and monitoring the field strength meter via a remote field strength indicator outside the enclosure while adjusting the continuous-wave to the antenna.
b. The test is performed with the antenna facing the front and back sides of the EUT with. Both vertical and horizontal polarizations from antenna are tested.

10.4. Test results

PASS

Temperature	:	17.5°C
Humidity	:	475%
Atmospheric Pressure	:	101kpa
Test Engineer	:	Zhuo Guixin
Test Date	:	2025-01-04

☒ 80M-1000MHz:

Freq. Range (MHz)	Field	Modulation	Polarity	Position (°)	Actual criterion	Required performance criterion	Result
80-1000	3V/m	AM, 80%	H / V	0, 90,180, 270	A	A	Pass

☒ Spot frequency:

Freq (MHz)	Field	Modulation	Polarity	Position (°)	Actual criterion	Required performance criterion	Result
1800, 2600, 3500, 5000	3V/m	AM, 80%	H / V	0, 90,180, 270	A	A	Pass

☐ Additional spot frequency:

Freq (MHz)	Field	Modulation	Polarity	Position (°)	Actual criterion	Required performance criterion	Result
80, 120, 160, 230, 434, 460, 600, 863, 900	3V/m	AM, 80%	H / V	0, 90,180, 270	N/A	N/A	N/A

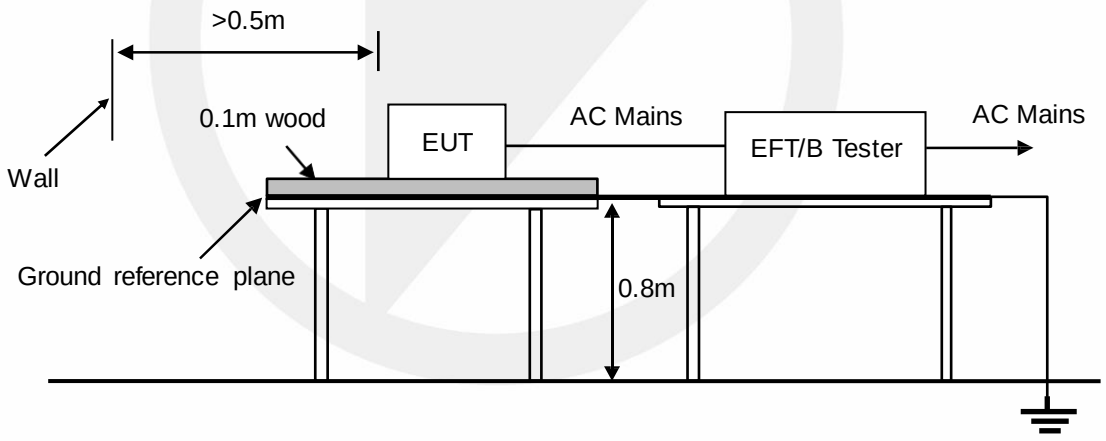
11. ELECTRICAL FAST TRANSIENT/BURST IMMUNITY TEST

11.1. Test Specification

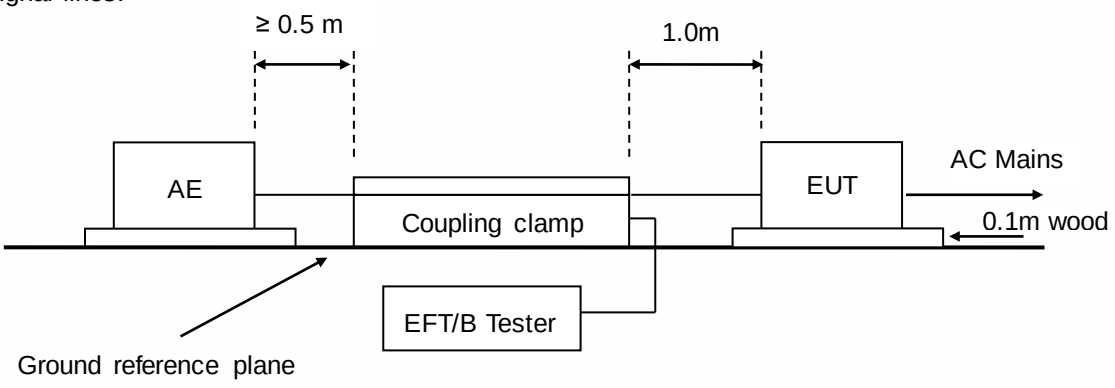
Test standard	:	SANS 2335/CISPR 35
Basic standard	:	IEC 61000-4-4
Performance criterion	:	B
Test level	:	☒1kV, AC mains power ports ☐0.5kV, DC network power ports ☐0.5kV, Analogue/digital data ports
Repetition frequency	:	☒5kHz, ☐100kHz(Only xDSL ports)
Tr/Th:	:	5/50ns
Burst period	:	300ms
Test time :	:	120s

11.2. Block Diagram of Test Setup

AC Lines:



Signal lines:



11.3. Test Procedure

The EUT is put on the table that is 0.8 meter high above the ground. This reference ground plane shall project beyond the EUT by at least 0.1m on all sides and the minimum distance between EUT and all other conductive structure, except the ground plane beneath the EUT, shall be more than 0.5m.

11.4. Test Results

PASS

Temperature	:	19.2°C
Humidity	:	47%
Atmospheric Pressure	:	101kpa
Test Engineer	:	Zhuo Guixin
Test Date	:	2025-01-04

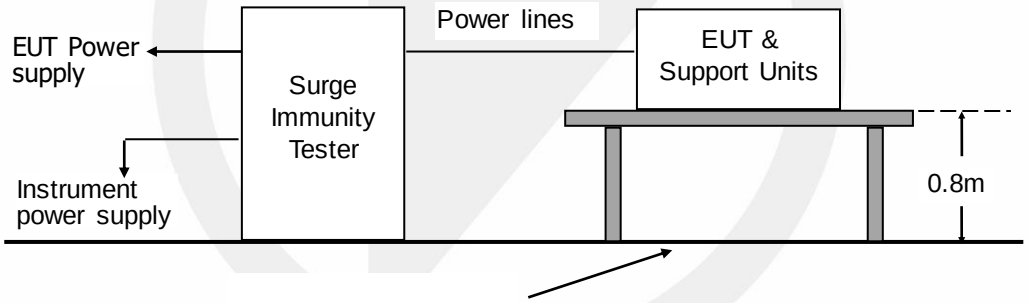
Injection Line	Voltage (kV)	Injected Method	Actual criterion	Required performance criterion	Result (Pass/Fail)
☒ AC mains power ports	± 1	☒ CDN ☐ Direct injection ☐ Capacitive coupling clamp	A	B	Pass
☐ DC network power ports	± 0.5	☐ CDN ☐ Direct injection ☐ Capacitive coupling clamp	N/A	N/A	N/A
☐ Analogue/digital data ports (Wired network port)	± 0.5	☐ CDN ☐ Direct injection ☒ Capacitive coupling clamp	N/A	N/A	N/A
☐ Analogue/digital data ports (Broadcast receiver tuner port)	± 0.5	☐ CDN ☐ Direct injection ☒ Capacitive coupling clamp	N/A	N/A	N/A

12.SURGE IMMUNITY TEST

12.1.Test Specification

Test standard	:	SANS 2335/CISPR 35
Basic standard	:	IEC 61000-4-5
Test level	:	☒1kV, Line to Line, AC mains power ports, Criterion B ☐2kV, Line to Earth, AC mains power ports, Criterion B ☐0.5kV, Line to Reference ground, DC network power ports, Criterion B ☐1.0kV, Lines to Ground, Unshielded symmetrical, Criterion C ☐4.0kV, Lines to Ground, Unshielded symmetrical, Criterion C ☐0.5kV, Shield to ground, Coaxial or shielded port, Criterion B
Number of surges	:	5 (for each combination of parameters)
Repetition rate	:	1 minute / time
Polarity:	:	Positive / Negative
Phase angle:	:	90º, 270º (Only AC mains power ports)

12.2.Block Diagram of Test Setup



12.3.Test Procedure

This test simulates a lightning event by inducing transients onto the AC/DC power supply lines in common mode (Line to Ground) and differential mode (Line to Line). Each device was tested in a total of two surge configurations: Line to Ground (L-G): Combination Wave, Line to Protective Earth with 9uF and 10Ohm and Neutral to Protective Earth with 9uF and 10Ohm, common mode, generator earthed.
Line to Line (L-L): Combination Wave,
Line to Neutral with 18uF, differential mode, generator floated.
2 ohm : the source impedance of the low-voltage power supply network.
12 ohm : the source impedance of the low-voltage power supply network and ground.

a. If not otherwise specified the surges have to be applied synchronized to the voltage phase at the zero-crossing and the peak value of the a.c. voltage wave (positive and negative).
b. The surges have to be applied line to line and line to earth. When testing line to earth, the test voltage has to be applied successively between each of the lines and earth, if there is no other specification.
c. The test procedure shall also consider the non-linear current-voltage characteristics of the equipment under test. Therefore the test voltage has to be increased by steps up to the test level specified in the product standard or test plan. All lower levels including the selected test level shall be satisfied.
d. For testing the secondary protection, the output voltage of the generator shall be increased up to the worst-case voltage breakdown level (let-through level) of the primary protection.

e. Testing shall be performed according to a Test Plan, which shall be included in the test report.
f. To find all critical points of the duty cycle of the equipment, a sufficient number of positive and negative test pulses shall be applied.

12.4. Test results

PASS

Temperature	:	19.2°C
Humidity	:	47%
Atmospheric Pressure	:	101kpa
Test Engineer	:	Zhuo Guixin
Test Date	:	2025-01-04

☒ AC mains power ports:

Coupling Line	Voltage (kV)	Waveform (μs)	Polarity	Actual criterion	Required performance criterion	Result (Pass/Fail)
☒ Line to line	0.5, 1	1.2/50 (8/20)	Pos./ Neg.	A	B	Pass
☐ Line to earth	0.5, 1, 2	1.2/50 (8/20)	Pos./ Neg.	N/A	B	N/A

☐ DC network power ports:

Coupling Line	Voltage (kV)	Waveform (μs)	Polarity	Actual criterion	Required performance criterion	Result (Pass/Fail)
Line to Reference ground	0.5	1.2/50 (8/20)	Pos./ Neg.	N/A	B	N/A

☐ Analogue/digital data ports:

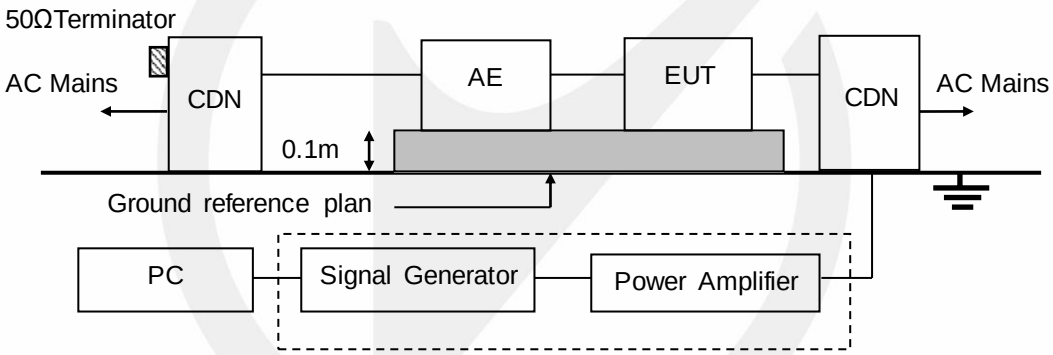
Port type	Coupling Line	Voltage (kV)	Waveform (μs)	Polarity	Actual criterion	Required performance criterion	Result (Pass/Fail)
☐ Unshielded symmetrical (Wired network port)	Lines to ground	0.5, 1	10/700 (5/320)	Pos./ Neg.	N/A	C	N/A
☐ Unshielded symmetrical (……)	Lines to ground	0.5, 1	10/700 (5/320)	Pos./ Neg.	N/A	C	N/A
☐ Unshielded symmetrical	Lines to ground	0.5, 1, 2, 4	10/700 (5/320)	Pos./ Neg.	N/A	C	N/A
☐ Coaxial or shielded (Broadcast receiver tuner port)	Shield to ground	0.5	1.2/50 (8/20)	Pos./ Neg.	N/A	C	N/A
☐ Coaxial or shielded (……)	Shield to ground	0.5	1.2/50 (8/20)	Pos./ Neg.	N/A	C	N/A

13.CONTINUOUS INDUCED RF DISTURBANCES

13.1.Test Specification

Test standard	:	SANS 2335/CISPR 35
Basic standard	:	IEC 61000-4-6
Performance criterion	:	A
Frequency range & Test level	:	0.15M to 10MHz, 3V 10M to 30MHz, 3V to 1V 30M to 80MHz, 1V
Modulation	:	AM 80%, 1kHz sine-wave
Frequency Step	:	1% of fundamental

13.2.Block Diagram of Test Setup



13.3.Test Procedure

a. The EUT shall be operated within its intended climatic conditions. The temperature and relative humidity should be recorded.
b. The EUT is placed on a 0.1m high test table, and a well grounded cable is connected to metallic plane above the test table.
c. All cables/wires must be laid out on test plate (3cm in thickness),and the EUT is set up on test plate (10 cm in thickness) as shown in test setup photo, and the cables/wires must not be in mid-air, they should be touching the surface of test plate. Ensure that the EUT is properly connected to the accessory equipment.
d. The test shall be performed with the test generator connected to each of the coupling and decoupling devices in turn while the other non-excited RF-input ports of the coupling devices are terminated by a 50 ohm load resistor.
e. The frequency range is swept from 150 kHz to 80 MHz, using the signal levels established during the setting process, and with the disturbance signal 80% amplitude modulated with a 1 kHz sine wave, pausing to adjust the RF-signal level or to switch coupling devices as necessary. The rate of sweep shall no exceed 1.5 x 10-3 decades/s. Where the frequency is swept incrementally, the step size shall no exceed 1% of the start and thereafter 1% of the preceding frequency value.
f. The dwell time at each frequency shall not be less than the time necessary for the EUT to be exercised, and able to respond. Sensitive frequencies e.g. clock frequency (ies) and harmonics or frequencies of dominant interest shall be analyzed separately.

g. Attempts should be made to fully exercise the EUT during testing, and to fully interrogate all exercise modes selected for susceptibility
h. Testing shall be performed according to a Test Plan, which shall be included in the test report.

13.4. Test results

PASS

Temperature	:	19.2°C
Humidity	:	47%
Atmospheric Pressure	:	101kpa
Test Engineer	:	Zhuo Guixin
Test Date	:	2025-01-04

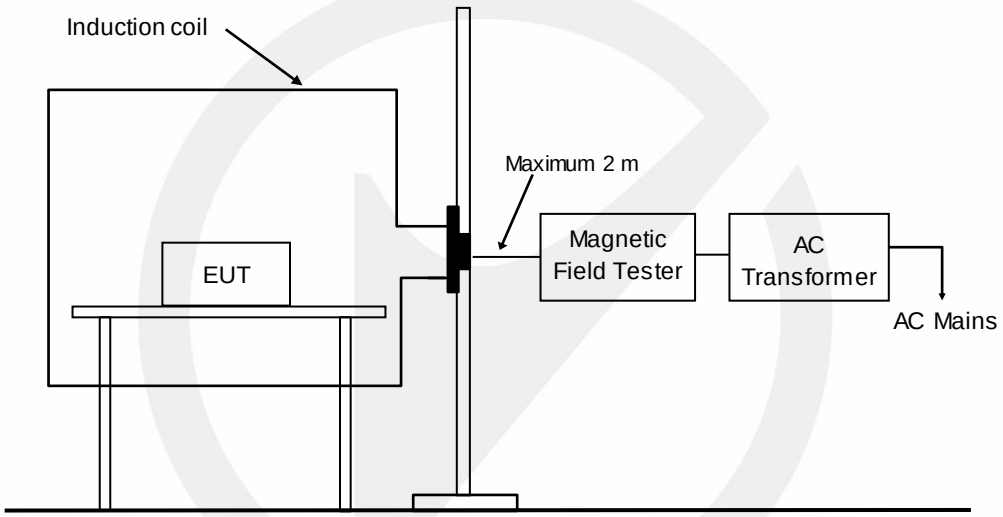
Range (MHz)	Levers (V)	Injection port	Coupling type	Actual criterion	Required performance criterion	Result (Pass/Fail)
0.15-10	3	☒AC mains power ports	☒CDN ☐EM Clamp ☐Current Clamp ☐Direct injection	A	A	Pass
10-30	3-1					
30-80	1					
0.15-10	3	☐DC network power ports	☒CDN ☐EM Clamp ☐Current Clamp ☐Direct injection	N/A	N/A	N/A
10-30	3-1					
30-80	1					
0.15-10	3	☐Analogue/digital data ports (Wired network port)	☐CDN ☒EM Clamp ☐Current Clamp ☐Direct injection	N/A	N/A	N/A
10-30	3-1					
30-80	1					
0.15-10	3	☐Analogue/digital data ports (Broadcast receiver tuner port)	☐CDN ☐EM Clamp ☒Current Clamp ☐Direct injection	N/A	N/A	N/A
10-30	3-1					
30-80	1					
0.15-10	3	☐Analogue/digital data ports (……)	☐CDN ☐EM Clamp ☒Current Clamp ☐Direct injection	N/A	N/A	N/A
10-30	3-1					
30-80	1					

14.POWER FREQUENCY MAGNETIC FIELD

14.1.Test Specification

Test Standard	:	SANS 2335/CISPR 35
Basic Standard	:	IEC 61000-4-8
Performance criterion	:	A
Test level	:	1A/m

14.2.Block Diagram of Test Setup



GRP: Ground reference plane
EUT: Equipment under test

14.3.Test Procedure

The EUT is placed in the middle of a induction coil (1*1m), under which is a 1*1*0.1m (high) table, this small table is also placed on a larger table, 0.8 m above the ground. Both horizontal and vertical polarization of the induction coil is set on test, so that each side of the EUT is affected by the magnetic field. Also can reach the same aim by change the position of the EUT.

14.4. Test Results

PASS

Temperature	:	19.2°C
Humidity	:	47%
Atmospheric Pressure	:	101kpa
Test Engineer	:	Zhuo Guixin
Test Date	:	2025-01-04

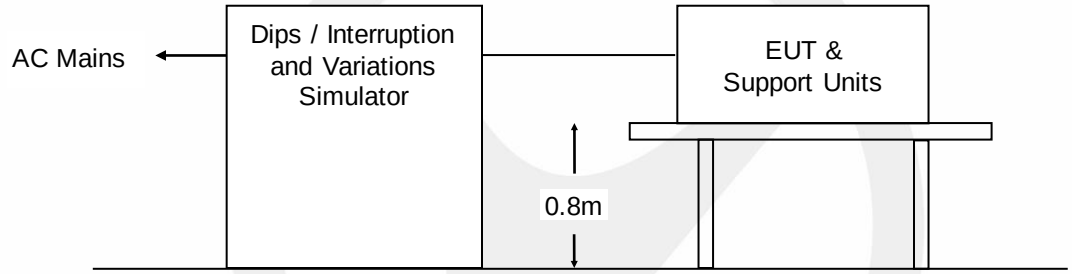
Test Level (A/m)	Frequency	Testing Duration	Coil Orientation	Actual criterion	Required performance criterion	Result (Pass/Fail)
1	☒ 50Hz ☒ 60Hz	5 mins	☒ x-axis ☒ y-axis ☒ z-axis	A	A	Pass

15. VOLTAGE DIPS AND INTERRUPTIONS TEST

15.1. Test Specification

Test standard	:	SANS 2335/CISPR 35
Basic standard	:	IEC 61000-4-11
Test level	:	☒0%, 0.5 period, Criterion B
		☒70%, 25 periods for 50Hz, Criterion C
		☒0%, 250 periods for 50Hz, Criterion C

15.2. Block Diagram of Test Setup



15.3. Test Procedure

a. Where the equipment has a rated voltage the following shall apply - If the voltage range does not exceed 20% of the lower voltage specified for the rated voltage range, a single voltage within that range may be specified as a basis for test level specification.
- In all other cases, the test procedure shall be applied for both the lowest and highest voltages declared in the voltage range.
b. Test Conditions
- Select operated voltage and frequency of EUT - Test of interval : 10 sec.
- Level and duration : Sequence of 3 dips/interrupts.
- Voltage rise (and fall) time : 1.5 μs.

15.4. Test results

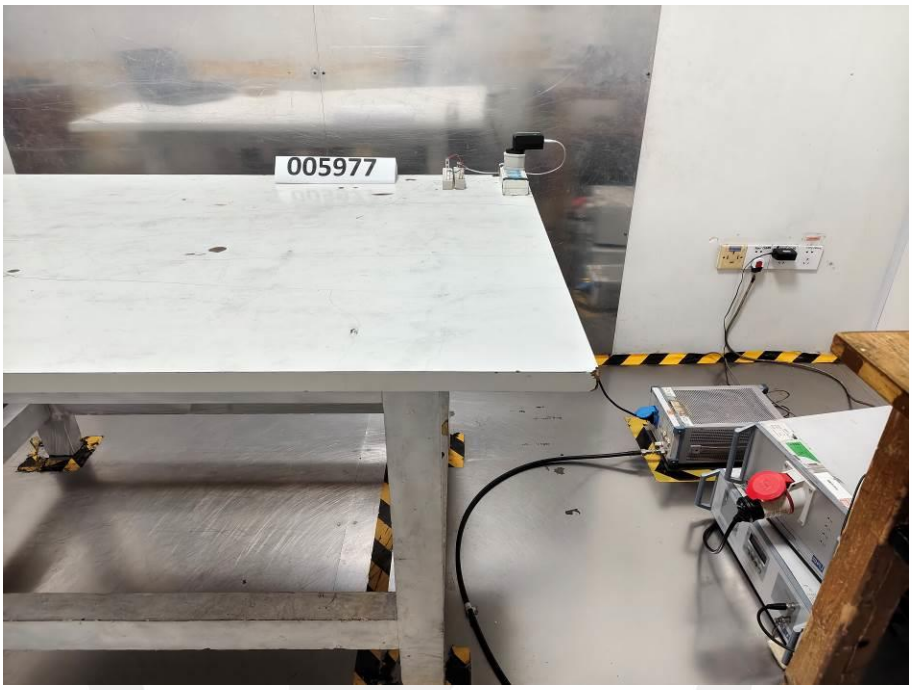
PASS

Temperature	:	19.2°C
Humidity	:	47%
Atmospheric Pressure	:	101kpa
Test Engineer	:	Zhuo Guixin
Test Date	:	2025-01-04

	Test Level (% UT)	Phase angle (°)	Input Voltage (V)	Freq (Hz)	Duration (periods)	Actual criterion	Required performance criterion	Result (Pass /Fail)
☒Voltage dips	0%	0º, 180º	AC 220V	50	0.5	A	B	Pass
☒Voltage dips	70%	0º, 180º	AC 220V	50	25	A	C	Pass
☒Voltage interruptions	0%	0º, 180º	AC 220V	50	250	B	C	Pass

16.PHOTOGRAPHS

16.1.Photos of Conducted Emissions from the AC Mains Power Ports





16.2. Photos of Radiation Emission Measurement

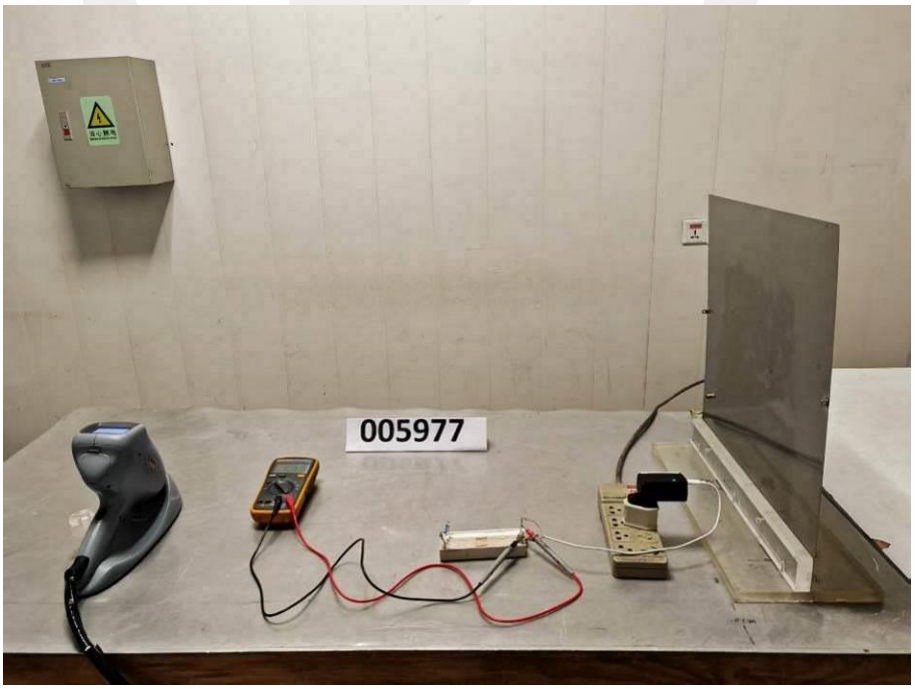




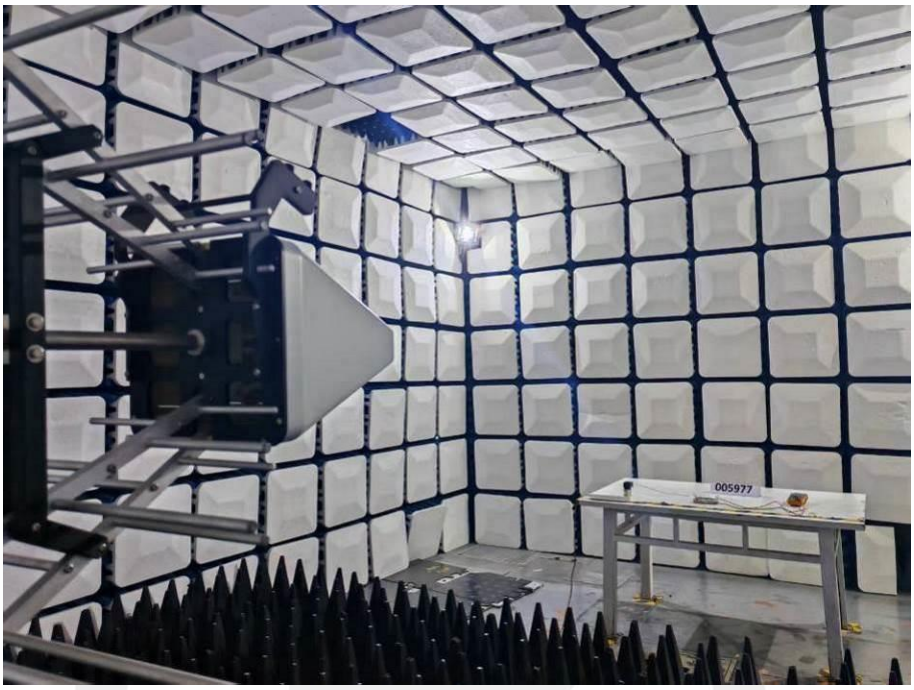
16.3. Photo of Harmonic / Flicker Measurement



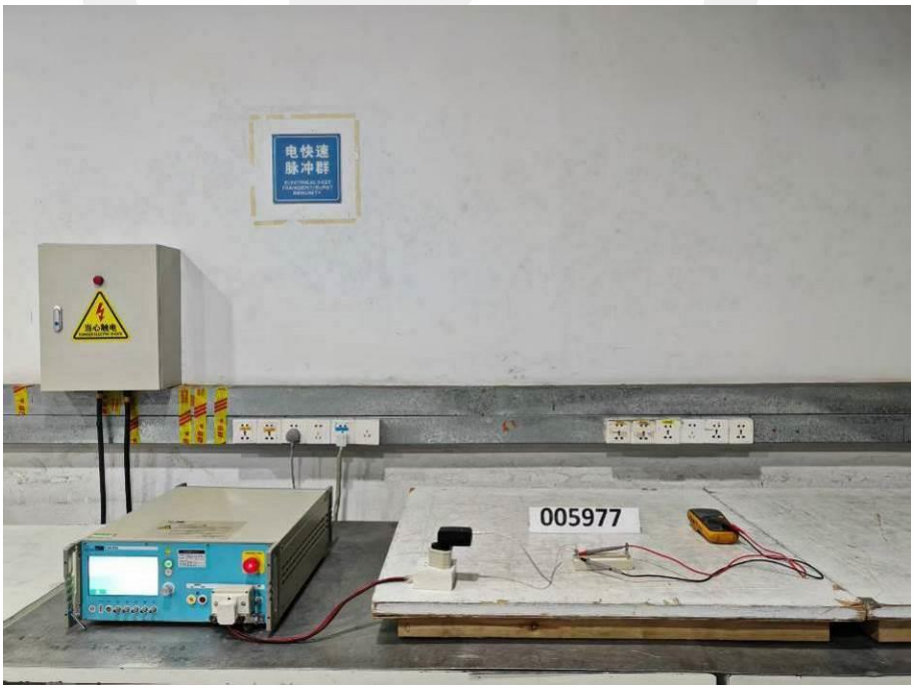
16.4. Photo of Electrostatic Discharge Test



16.5. Photo of Continuous RF Electromagnetic Field Disturbances



16.6. Photos of Electrical Fast Transient / Burst Test



16.7. Photos of Surge Test



16.8. Photos of Continuous Induced RF Disturbances Test



16.9.Photo of Power Frequency Magnetic Field Test



16.10.Photo of Voltage Dips and Interruption Immunity Test

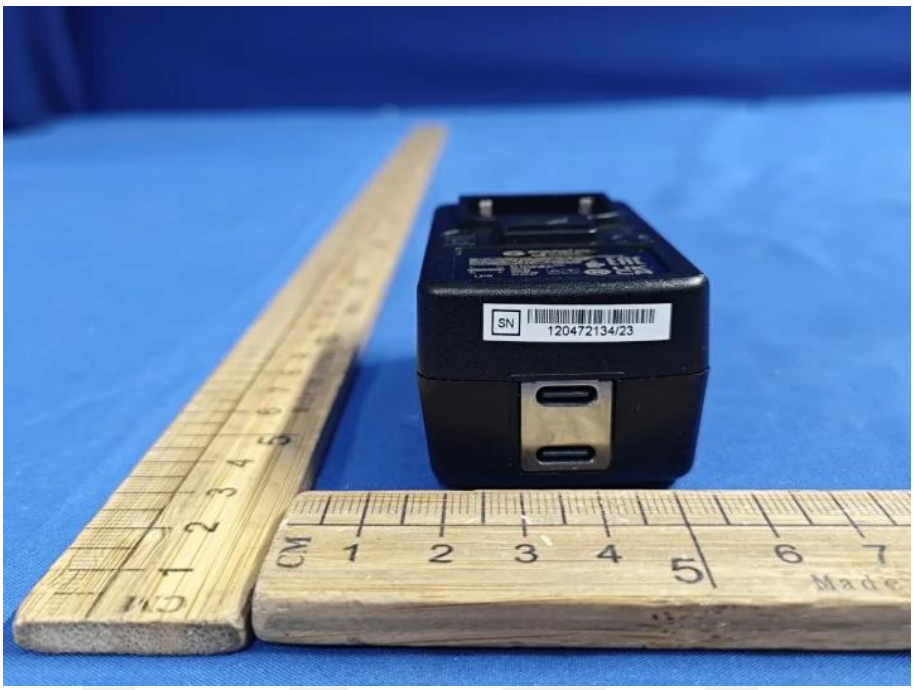


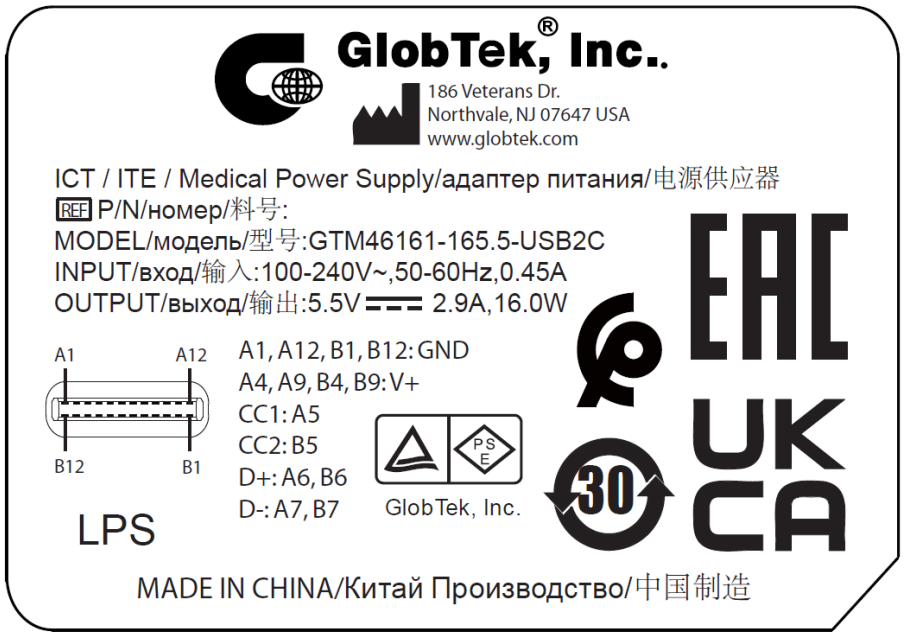
APPENDIX A: Photos of EUT

GTM46161-165.5-USB2C






SN
120472134/23
CM 1 2 3 4 5 6 7

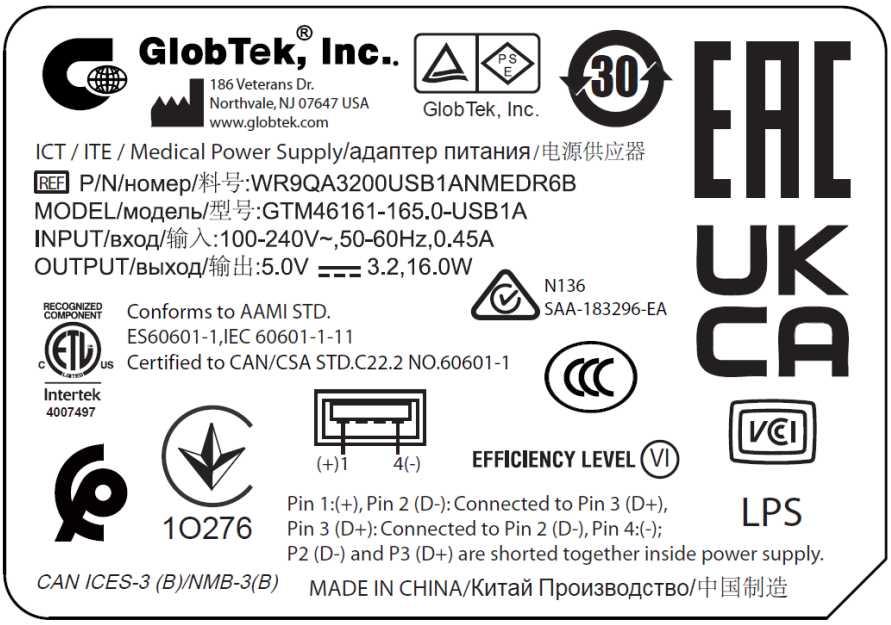

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REF P/N/номер/料号:
MODEL/модель/型号:GTM46161-165.5-USB2C
INPUT/вход/输入:100-240V~,50-60Hz,0.45A
OUTPUT/выход/输出:5.5V ⎓ 2.9A,16.0W
A1
A12
B12
B1
A1, A12, B1, B12: GND
A4, A9, B4, B9: V+
CC1: A5
CC2: B5
D+: A6, B6
D-: A7, B7
GlobTek, Inc.
LPS
MADE IN CHINA/Китай Производство/中国制造

GTM46161-165.0-USB1A



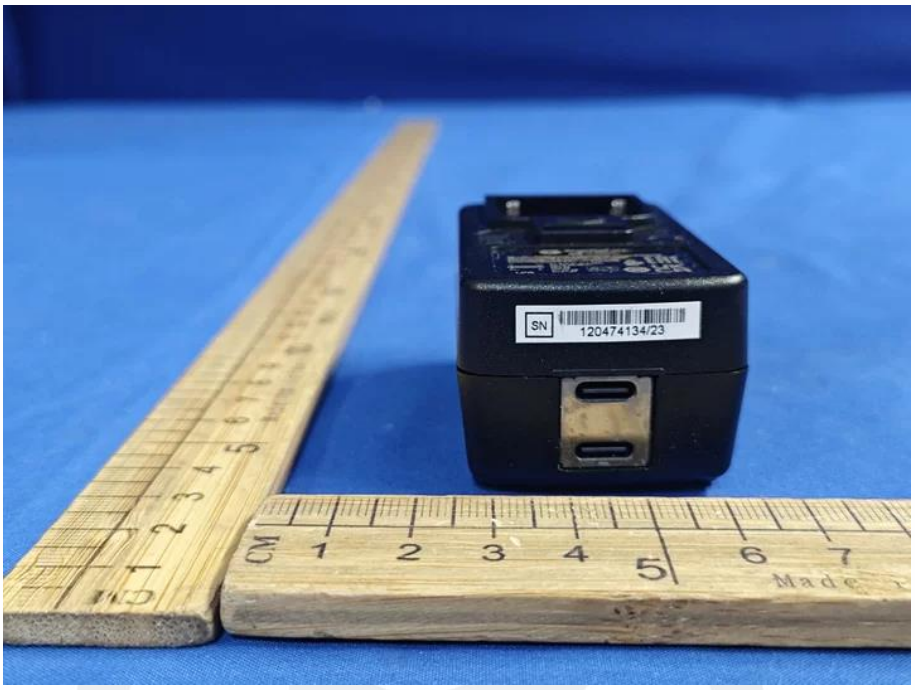


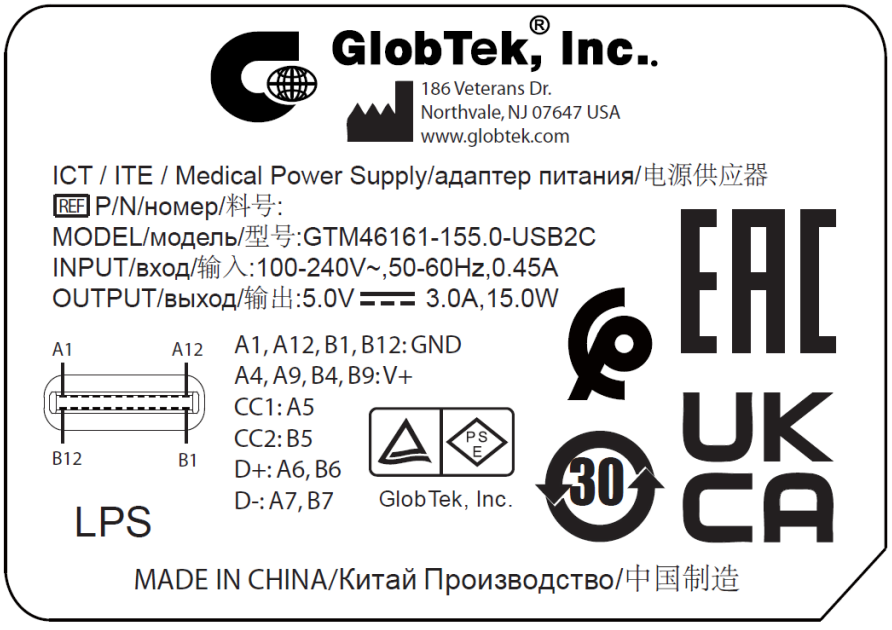



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REF P/N/номер/料号:WR9QA3200USB1ANMEDR6B
MODEL/модель/型号:GTM46161-165.0-USB1A
INPUT/вход/输入:100-240V~,50-60Hz,0.45A
OUTPUT/выход/输出:5.0V 3.2,16.0W
N136
SAA-183296-EA
Conforms to AAMI STD.
ES60601-1,IEC 60601-1-11
Certified to CAN/CSA STD.C22.2 NO.60601-1
Intertek
4007497
(+)1
4(-)
EFFICIENCY LEVEL VI
1O276
Pin 1:(+), Pin 2 (D-): Connected to Pin 3 (D+),
Pin 3 (D+): Connected to Pin 2 (D-), Pin 4:(-);
P2 (D-) and P3 (D+) are shorted together inside power supply.
LPS
CAN ICES-3 (B)/NMB-3(B)
MADE IN CHINA/Китай Производство/中国制造


Made in China

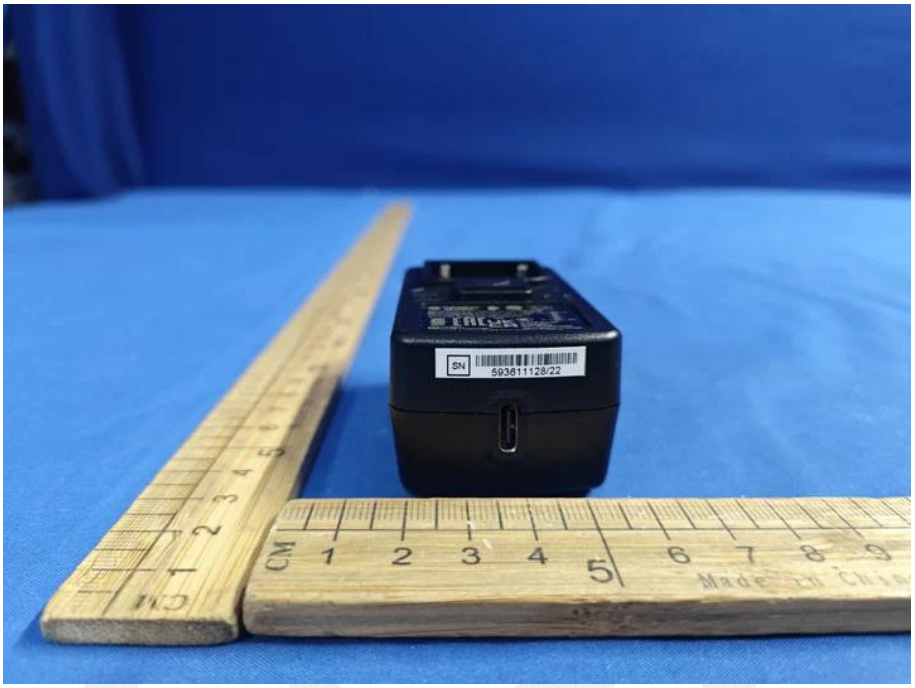

Made in China

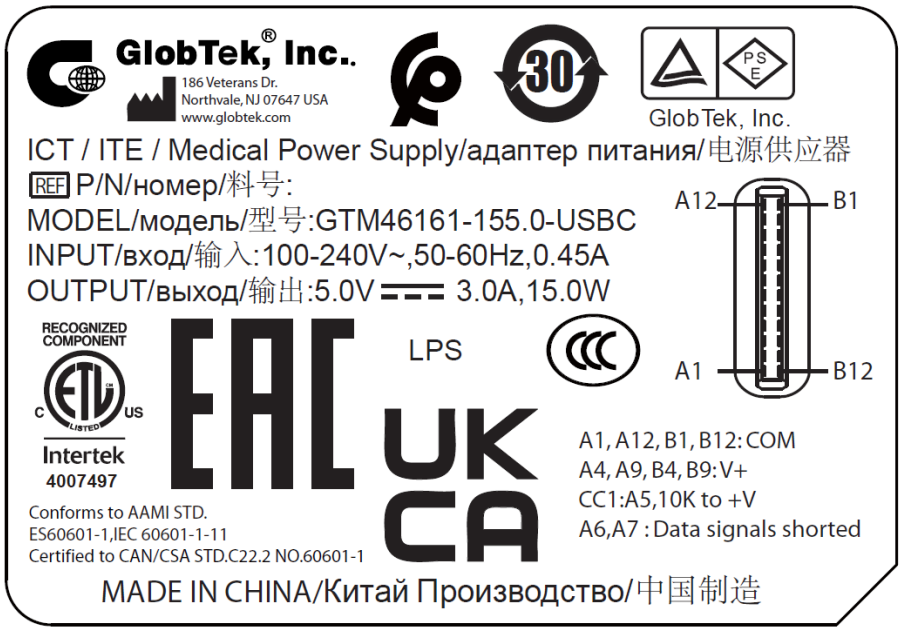

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REF P/N/номер/料号:
MODEL/модель/型号:GTM46161-155.0-USB2C
INPUT/вход/输入:100-240V~,50-60Hz,0.45A
OUTPUT/выход/输出:5.0V 3.0A,15.0W
A1
A12
B12
B1
A1, A12, B1, B12: GND
A4, A9, B4, B9: V+
CC1: A5
CC2: B5
D+: A6, B6
D-: A7, B7
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LPS
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SN
593611128/22
CM 1 2 3 4 5 6 7 8 9


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REF P/N/номер/料号:
MODEL/модель/型号:GTM46161-155.0-USBC
INPUT/вход/输入:100-240V~,50-60Hz,0.45A
OUTPUT/выход/输出:5.0V 3.0A,15.0W
A12
B1
A1
B12
RECOGNIZED COMPONENT
Intertek
4007497
LPS
A1, A12, B1, B12: COM
A4, A9, B4, B9: V+
CC1:A5,10K to +V
A6,A7 : Data signals shorted
Conforms to AAMI STD.
ES60601-1,IEC 60601-1-11
Certified to CAN/CSA STD.C22.2 NO.60601-1
MADE IN CHINA/Китай Производство/中国制造

APPENDIX B: Critical Component List

Object/part no.	Manufacturer/ trademark	Type/model	Technical data	Standard	Mark(s) of conformity.
Plastic enclosure and Blade holder	SABIC INNOVATIVE PLASTICS B V	C2950	V-0, 85°C, Min. thickness: 1.5mm	UL 94, IEC/EN 62368-1	UL E45329 and tested with appliance
Alt.	SABIC INNOVATIVE PLASTICS B V	CX7211 915R(GG) 945(GG)	V-0, 90°C, Min. thickness: 1.5mm	UL 94, IEC/EN 62368-1	UL E45329 and tested with appliance
Alt.	FORMOSA CHEMICALS & FIBRE CORP PLASTICS DIV	AC310(+)	V-0, 85°C, Min. thickness: 1.5mm	UL 94, IEC/EN 62368-1	UL E162823 and tested with appliance
Alt.	TEIJIN CHEMICALS LTD	LN-1250G	V-0, 125°C, Min. thickness: 1.5mm	UL 94, IEC/EN 62368-1	UL E50075 and tested with appliance
Alt.	SABIC JAPAN L L C	915R(GG) 945(GG)	V-0, 125°C, Min. thickness: 1.5mm	UL 94, IEC/EN 62368-1	UL E207780 and tested with appliance
PCB	WALEX ELECTRONIC (WUXI) CO LTD	T2, T2A, T2B, T4	V-0, 130°C, Min. 1.2 mm thickness	UL 796, IEC/EN 62368-1	UL E154355 and tested with appliance
Alt.	DONGGUAN HE TONG ELECTRONICS CO LTD	CEM1, 2V0, FR4	V-0, 130°C, Min. 1.2 mm thickness	UL 796, IEC/EN 62368-1	UL E243157 and tested with appliance
Alt.	CHEERFUL ELECTRONIC	02, 03, 03A	V-0, 130°C, Min. 1.2 mm thickness	UL 796, IEC/EN 62368-1	UL E199724 and tested with appliance
Alt.	DONGGUAN DAYSUN ELECTRONIC CO LTD	DS2	V-0, 130°C, Min. 1.2 mm thickness	UL 796, IEC/EN 62368-1	UL E251754 and tested with appliance
Alt.	SHANGHAI AREX PRECISION ELECTRONIC CO LTD	02V0, 03V0, 04V0	V-0, 130°C, Min. 1.2 mm thickness	UL 796, IEC/EN 62368-1	UL E186016 and tested with appliance
Alt.	SHENZHEN TONGCHUANG XIN ELECTRONICS CO LTD	TCX	V-0, 130°C, Min. 1.2 mm thickness	UL 796, IEC/EN 62368-1	UL E250336 and tested with appliance
Alt.	PACIFIC WIN INDUSTRIAL LTD	PW-02, PW-03	V-0, 130°C, Min. 1.2 mm thickness	UL 796, IEC/EN 62368-1	UL E228070 and tested with appliance
Alt.	GOLDEN TRIANGLE PCB & TECHNOLOGIE S LTD	GT-D	V-0, 130°C, Min. 1.2 mm thickness	UL 796, IEC/EN 62368-1	UL E340752 and tested with appliance
Alt.	KUOTIANG ENT LTD	C-2, C-2A, C-4	V-0, 130°C, Min. 1.2 mm thickness	UL 796, IEC/EN 62368-1	UL E227299 and tested with appliance
Alt.	KINGBOARD LAMINATES HOLDINGS LTD	KB-3151C, KB-5150	V-0, 130°C, Min. 1.2 mm thickness	UL 796, IEC/EN 62368-1	UL E123995 and tested with appliance
Alt.	SHENZHEN JINDIAN PRECISION CIRCUIT CO LTD	JD-1, JD-1A	V-0, 130°C, Min. 1.2 mm thickness	UL 796, IEC/EN 62368-1	UL E347010 and tested with appliance
Alt.	Interchangeable	Interchangeable	V-0, 130°C, Min.	UL 796,	UL

Object/part no.	Manufacturer/ trademark	Type/model	Technical data	Standard	Mark(s) of conformity.
Fusible resistor (RF1)	ANHUI CHANGSHENG ELECTRONICS CO LTD	RXF21-1W	1 Ω, 1 W	UL 248-1, UL 248-14, IEC/EN 62368-1	UL E306095 and tested with appliance
Alt.	SHENZHEN GREAT ELECTRONICS CO LTD	RXF-1W	1 Ω, 1 W	UL 248-1, UL 248-14, IEC/EN 62368-1	UL E301541 and tested with appliance
Alt.	JIANGSU XINYANG ELECTRONIC COMPONENT CO LTD	RF10-1W	1 Ω, 1 W	UL 248-1, UL 248-14, IEC/EN 62368-1	UL E312842 and tested with appliance
Alt.	SHENZHEN KAYOCOTA ELECTRONICS CO LTD	FRKNP-1WS	1 Ω, 1 W	UL 248-1, UL 248-14, IEC/EN 62368-1	UL E318056 and tested with appliance
Alt.	TZAI YUAN ENTERPRISE CO LTD	KNF1W	1 Ω, 1 W	UL 248-1, UL 248-14, IEC/EN 62368-1	UL E355632 and tested with appliance
Alt.	Yageo Components (Suzhou) Co. Ltd.	FKN	1 Ω, 1 W	UL 248-1, UL 248-14, IEC/EN 62368-1	UL E323780 and tested with appliance
Fuse (FS1) (For circuit diagram/ PCB layout type 1 & 2)	Conquer Electronics Co., Ltd.	MST series	T1 A or T2 A, 250V, LBC	IEC/EN 60127-1, IEC/EN 60127-3	VDE 40017118
Alt.	SUZHOU WALTER ELECTRONIC CO LTD	2000	T1 A or T2 A, 250V, LBC	IEC/EN 60127-1, IEC/EN 60127-3	VDE 40018790
Alt.	SUZHOU WALTER ELECTRONIC CO LTD	2010	T1 A or T2 A, 250V, LBC	IEC/EN 60127-1, IEC/EN 60127-3	VDE 40018781
Alt.	Bel Fuse Ltd.	RST	T1 A or T2 A, 250V, LBC	IEC/EN 60127-1, IEC/EN 60127-3	VDE 40011144
Alt.	Cooper Bussmann LLC	SS-5	T1 A or T2 A, 250V, LBC	IEC/EN 60127-1, IEC/EN 60127-3	VDE 40015513
Alt.	Walter Electronic Co. Ltd.	ICP series	T1 A or T2 A, 250V, LBC	IEC/EN 60127-1, IEC/EN 60127-3	VDE 40012824
Alt.	Shenzhen Lanson Electronics Co. Ltd.	SMT	T1 A or T2 A, 250V, LBC	IEC/EN 60127-1, IEC/EN 60127-3	VDE 40012592
Alt.	Das & Sons International Ltd.	385T	T1 A or T2 A, 250V, LBC	IEC/EN 60127-1, IEC/EN 60127-3	VDE 40008524
Fuse (RF1) (For circuit diagram/ PCB layout type 2)	Walter Electronic Co. Ltd.	ICP series	T1 A or T2 A, 250V, LBC	IEC/EN 60127-1, IEC/EN 60127-3	VDE 40012824
Alt.	Zhongshan Lanbao Electrical Appliances Co., Ltd.	RTI-10 Serie(s)	T1 A or T2 A, 250V, LBC	IEC/EN 60127-1, IEC/EN 60127-3	VDE 40017009

Object/part no.	Manufacturer/ trademark	Type/model	Technical data	Standard	Mark(s) of conformity.
Bridging-Capacitor (CY1, CY2) (optional)	TDK Corporation	CD	250Vac, 125°C, Max. 1000pF	IEC/EN 60384-14	VDE 40029780
Alt.	Success Electronics Co., Ltd.	SE	250Vac, 125°C, Max. 1000pF	IEC/EN 60384-14	VDE 40037211
Alt.	Success Electronics Co., Ltd.	SB	250Vac, 125°C, Max. 1000pF	IEC/EN 60384-14	VDE 40037221
Alt.	Murata Mfg. Co., Ltd.	KX	250Vac, 125°C, Max. 1000pF	IEC/EN 60384-14	VDE 40002831
Alt.	Walsin Technology Corp.	AH	250Vac, 125°C, Max. 1000pF	IEC/EN 60384-14	VDE 40001804
Alt.	JYA-NAY Co., Ltd.	JN	250Vac, 125°C, Max. 1000pF	IEC/EN 60384-14	VDE 40001831
Alt.	Haohua Electronic Co.	CT7	250Vac, 125°C, Max. 1000pF	IEC/EN 60384-14	VDE 40003902
Alt.	Hongzhi Enterprises Ltd.	Y	250Vac, 125°C, Max. 1000pF	IEC/EN 60384-14	VDE 40038760
Alt.	SHANTOU HIGH-NEW TECHNOLOGY DEVELOPMNT ZONE SONGTIAN ENTERPRISE CO LTD	CD	250Vac, 125°C, Max. 1000pF	IEC/EN 60384-14	VDE 40025754
Varistor MOV1	Joyin Co., Ltd.	JVR10N471K, JVR14N471K	300Vac, coating is V-0, 125 °C, 6KV/3KA, pulse test passed	IEC 61051-1, IEC 61051-2, IEC 61051-2-2	VDE 005937
Alt.	Centra Science Corp.	10D471K, 14D471K	300Vac, coating is V-0, 125 °C, 6KV/3KA, pulse test passed	IEC 61051-1, IEC 61051-2, IEC 61051-2-2	VDE 40008220
Alt.	Thinking Electronic Industrial Co., Ltd.	TVR10471K, TVR14471K, TFV10S471K, TVR10621K	300Vac, coating is V-0, 125 °C, 6KV/3KA, pulse test passed	IEC 61051-1, IEC 61051-2, IEC 61051-2-2	VDE 005944
Alt.	Success Electronics Co., Ltd.	SVR10D471K, SVR14D471K	300Vac, coating is V-0, 125 °C, 6KV/3KA, pulse test passed	IEC 61051-1, IEC 61051-2, IEC 61051-2-2	VDE 40030401
Alt.	Ceramate Techn. Co., Ltd.	GNR10D471K, GNR14D471K	300Vac, coating is V-0, 125 °C, 6KV/3KA, pulse test passed	IEC 61051-1, IEC 61051-2, IEC 61051-2-2	VDE 40031745
Alt.	Brightking (Shenzhen) Co., Ltd.	14D471K, 10D471K	300Vac, coating is V-0, 125 °C, 6KV/3KA, pulse test passed	IEC 61051-1, IEC 61051-2, IEC 61051-2-2	VDE 40027827

Object/part no.	Manufacturer/ trademark	Type/model	Technical data	Standard	Mark(s) of conformity.
Alt.	Lien Shun Electronics Co., Ltd.	10D471K, 14D471K	300Vac, coating is V-0, 125 °C, 6KV/3KA, pulse test passed	IEC 61051-1, IEC 61051-2, IEC 61051-2-2	VDE 40005858
Alt.	HONGZHI ENTERPRISES LTD	HEL-10D471K, HEL-14D471K	300Vac, coating is V-0, 125 °C, 6KV/3KA, pulse test passed	IEC 61051-1, IEC 61051-2, IEC 61051-2-2	VDE 40008621
Alt.	GUANGXI NEW FUTURE INFORMATION INDUSTRY CO LTD	10D471K, 14D471K	300Vac, coating is V-0, 125 °C, 6KV/3KA, pulse test passed	IEC 61051-1, IEC 61051-2, IEC 61051-2-2	VDE 40030322
Alt.	Thinking Electronic Industrial Co., Ltd.	TVR10471-M	300Vac, coating is V-0, 125 °C, 6KV/3KA, pulse test passed	IEC 61051-1, IEC 61051-2, IEC 61051-2-2	VDE 40036061
Alt.	SHANTOU HIGH-NEW TECHNOLOGY DEVELOPMNT ZONE SONGTIAN ENTERPRISE CO LTD	10D471K, 14D471K, 10D621K	300Vac, coating is V-0, 125 °C, 6KV/3KA, pulse test passed	IEC 61051-1, IEC 61051-2, IEC 61051-2-2	VDE 40023049
Alt.	Guangdong Huiwan Electronics Technology Co Ltd	V-471K-10D, V-471K-10E V-471K-14D, V-471-14E	300Vac, coating is V-0, 125 °C, 6KV/3KA, pulse test passed	IEC 61051-1, IEC 61051-2, IEC 61051-2-2	VDE 40043880
Alt.	XIAMEN SET ELECTRONICS CO LTD	TFV8S471K, TFV10S471K	300Vac, coating is V-0, 125 °C, 6KV/3KA, pulse test passed	IEC 61051-1, IEC 61051-2, IEC 61051-2-2	TUV J 50554061
Thermal conductive pad	Suzhou Springgrass Electronic Technology Co., LTD	HRTP-M16	V-0, 130°C, Min. thickness: 5.8mm	UL 94 IEC/EN 62368-1	UL E528141 and tested with appliance
Alt.	SUZHOU HUIMEI PACKAGING PRODUCTS CO LTD	HM-300	V-0, 130°C, Min. thickness: 5.8mm	UL 94 IEC/EN 62368-1	UL E516470 and tested with appliance
Alt.	PIONEER MATERIAL PRECISION TECH	PMP-P-300	V-0, 130°C, Min. thickness: 5.8mm	UL 94 IEC/EN 62368-1	UL E153203 and tested with appliance
Transformer (T1)	GlobTek, Shan Dong Boam Electric Co Ltd, WUXI HAOPUWEI ELECTRONICS CO.,LTD, ENG	XF01036	Class B	IEC/EN 62368-1	Tested with appliance
-Insulation system	GLOBTEK INC	GTX-130-TM	Class B	UL 1446 IEC/EN 62368-1	UL E243347 and tested with appliance
Alt.	ENG ELECTRIC CO LTD	ENG130-1	Class B	UL 1446 IEC/EN 62368-1	UL E308897 and tested with appliance

Object/part no.	Manufacturer/ trademark	Type/model	Technical data	Standard	Mark(s) of conformity.
Alt.	SHAN DONG BOAM ELECTRIC CO LTD	BOAM-01 or B1	Class B	UL 1446 IEC/EN 62368-1	UL E252329 and tested with appliance
Alt.	WUXI HAOPUWEI ELECTRONICS CO LTD	ZT-130	Class B	UL 1446 IEC/EN 62368-1	UL E315275 and tested with appliance
-Magnet wire (primary)	PACIFIC ELECTRIC WIRE & CABLE (SHENZHEN) CO LTD	UEWN/U, UEWS/U	MW28-C, 130°C	UL 1446 IEC/EN 62368-1	UL E201757 and tested with appliance
Alt.	JUNG SHING WIRE CO LTD	UEW-4, UEY-2	MW75C, 130°C	UL 1446 IEC/EN 62368-1	UL E174837 and tested with appliance
Alt.	JIANGSU HONGLIU MAGNET WIRE TECHNOLOGY CO LTD	2UEW/130	MW75-C, 130°C	UL 1446 IEC/EN 62368-1	UL E335065 and tested with appliance
Alt.	CHANGZHOU DAYANG WIRE & CABLE CO LTD	2UEW/130	MW75-C, 130°C	UL 1446 IEC/EN 62368-1	UL E158909 and tested with appliance
Alt.	WUXI JUFENG COMPOUND LINE CO LTD	2UEWB	MW75#, 130°C	UL 1446 IEC/EN 62368-1	UL E206882 and tested with appliance
Alt.	JIANGSU DARTONG M & E CO LTD	UEW	MW 75-C, 130°C	UL 1446 IEC/EN 62368-1	UL E237377 and tested with appliance
Alt.	SHANDONG SAINT ELECTRIC CO LTD	UEW/130	MW75#, 130°C	UL 1446 IEC/EN 62368-1	UL E194410 and tested with appliance
Alt.	ZHEJIANG LANGLI ELECTRIC EQUIPMENTS CO LTD	UEW	MW 79#, 130°C	UL 1446 IEC/EN 62368-1	UL E222214 and tested with appliance
Alt.	NINGBO JINTIAN NEW MATERIAL CO LTD	2UEW/155	MW 79#, 155°C	UL 1446 IEC/EN 62368-1	UL E227047 and tested with appliance
Alt.	HUIZHOU HUILI INDUSTRIAL CO LTD	MIW-B(x)	MW75#, 130°C	UL 1446 IEC/EN 62368-1	UL E322908 and tested with appliance
-Triple-insulated wire (Secondary)	Great Leoflon Industrial Co., Ltd.	TRW (B) Serie(s)	Class B, 130°C, reinforced insulation	IEC/EN 62368-1	VDE 136581
Alt.	KBI COSMOLINK CO.,LTD.	TIW-M Serie(s)	Class B, 130°C, reinforced insulation	IEC/EN 62368-1	VDE 138053
Alt.	Furukawa Electric Co., Ltd. Electronics	TEX-E	Class B, 130°C, reinforced insulation	IEC/EN 62368-1	VDE 006735
Alt.	TOTOKU ELECTRIC CO LTD	TIW-2	Class B, 130°C, reinforced insulation	IEC/EN 62368-1	VDE 40005152

Object/part no.	Manufacturer/ trademark	Type/model	Technical data	Standard	Mark(s) of conformity.
Alt.	E&B TECHNOLOGY CO LTD	E&B-XXXB, E&B-XXXB-1	Class B, 130°C, reinforced insulation	IEC/EN 62368-1	VDE 40023473
Alt.	SHENZHEN JIUDING NEW MATERIAL CO LTD	DTIW-B	Class B, 130°C, reinforced insulation	IEC/EN 62368-1	VDE 40037495
-Bobbin	CHANG CHUN PLASTICS CO LTD	T375J, T375HF, T373J	V-0, 150°C, thickness 0.45 mm min.	UL 94 IEC/EN 62368-1	UL E59481 and tested with appliance
Alt.	SUMITOMO BAKELITE CO LTD	PM-9820, PM-9630, PM-9823	V-0, 150°C, thickness 0.74 mm min.	UL 94 IEC/EN 62368-1	UL E41429 and tested with appliance
Alt.	Resonac Techno Service Corporation	CP-J-8800	V-0, 150°C, thickness 0.45 mm min.	UL 94 IEC/EN 62368-1	UL E514814 and tested with appliance
Alt.	CHANG CHUN PLASTICS CO LTD	4130	V-0, 150°C, thickness 0.45 mm min.	UL 94 IEC/EN 62368-1	UL E59481 and tested with appliance
-Insulating tape	3M COMPANY ELECTRICAL MARKETS DIV (EMD)	1350F-1, 1350T-1, 44	Min.130°C	UL 510A IEC/EN 62368-1	UL E17385 and tested with appliance
Alt.	HUIZHOU YAHUA ELECTRONIC TECHNOLOGY CO LTD	CT	Min.130°C	UL 510A IEC/EN 62368-1	UL E495875 and tested with appliance
Alt.	BONDTEC PACIFIC CO LTD	370S	Min.130°C	UL 510A IEC/EN 62368-1	UL E175868 and tested with appliance
Alt.	JINGJIANG YAHUA PRESSURE SENSITIVE GLUE CO LTD	PZ CT WF	Min.130°C	UL 510A IEC/EN 62368-1	UL E165111 and tested with appliance
Alt.	JINGJIANG JINGYI ADHESIVE PRODUCT CO LTD	JY25-A	Min.130°C	UL 510A IEC/EN 62368-1	UL E246950 and tested with appliance
Alt.	CHANG SHU LIANG YI TAPE INDUSTRY CO LTD	LY-XX	Min.130°C	UL 510A IEC/EN 62368-1	UL E246820 and tested with appliance
Alt.	SHEN ZHEN WEI CHUANG DA PACKAGING MATERIALS CO., LTD.	W-001	Min.130°C	UL 510A IEC/EN 62368-1	UL E333581 and tested with appliance
-PTFE tubing	Great Holding Industrial Co Ltd	TFT, TFS	Min. 300V, 200°C	UL 224 IEC/EN 62368-1	UL E156256 and tested with appliance

Object/part no.	Manufacturer/ trademark	Type/model	Technical data	Standard	Mark(s) of conformity.
Alt.	Shenzhen Woer Heat-Shrinkable Material Co Ltd	WF	600V, 200°C	UL 224 IEC/EN 62368-1	UL E203950 and tested with appliance
Alt.	Changyuan Electronics (Shenzhen) Co Ltd	CB-TT-T, CB-TT-S	Min. 300V, 200°C	UL 224 IEC/EN 62368-1	UL E180908 and tested with appliance

End of Report

Statement

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